

08-16-00

Express Mail Mailing Label
No.: EL 615 576 679 US

Date of Deposit: August 15, 2000

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1C893 U.S. PTO
09/639041

Pursuant to 37 CFR 1.53(b), transmitted herewith for filing is the patent application of

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Title: "PHOTOSENSOR SYSTEM AND DRIVE CONTROL METHOD THEREOF"

Priority Claim (35 U.S.C. 119) is made, based upon:

Japan No. 11-271882 September 27, 1999
Japan No. 11-370533 December 27, 1999

Enclosed herewith are:

[X] Specification (Description, Claims, Abstract): Pages 1 - 72; Number of claims 1 - 19
[X] Declaration and Power of Attorney [X] executed; [] unexecuted (supplied for information purposes)
[X] 18 Sheets of drawings, Figures 1 - 18D [X] Formal [] Informal
[X] Assignment and "Patents" Recordation Form Cover Sheet (PTO-1595) AND \$40. RECORDATION FEE.
[X] Certified copies of priority documents identified above
[X] Information Disclosure Statement; [X] Form PTO-1449
[] Preliminary Amendment
[] Verified Statement(s) Claiming Small Entity Status
[X] Receipt Postcard

	Number Filed	Number Extra	Rate	Calculations
Total Claims	<u>19</u>	<u>-20</u> = <u>0</u>	x \$18.00	= \$_____
Independent Claims	<u>2</u>	<u>- 3</u> = <u>0</u>	x \$78.00	= \$_____
MULTIPLE DEPENDENT CLAIMS			+ \$260.00	= \$_____
			BASIC FEE	\$ 690.00

To the extent not tendered by check, authorization is given to charge any fees under 37 CFR 1.16 and 1.17 during pendency of the application, or to credit any overpayment, to Deposit Account No. 06-1378. Duplicate copy of this letter is attached.

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Basis

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TITLE OF THE INVENTION

PHOTOSENSOR SYSTEM AND DRIVE CONTROL METHOD THEREOF

CROSS-REFERENCE TO RELATED APPLICATIONS

This application is based upon and claims the
5 benefit of priority from the prior Japanese Patent
Applications No. 11-271882, filed September 27, 1999;
and No. 11-370533, filed December 27, 1999, the entire
contents of which are incorporated herein by reference.

BACKGROUND OF THE INVENTION

10 This invention relates to a photosensor system
having a two-dimensionally arranged photosensor array,
and a method for drive-controlling the system.

15 Imaging apparatuses such as electronic still
cameras, video cameras, etc. have come to be very
widely used. These imaging apparatuses employ a solid-
state imaging device, such as a CCD (Charge Coupled
Device), which serves as a photoelectric converting
device for converting an image of a to-be-photographed
subject into an image signal. As well known, the CCD
20 has a structure in which photosensors (light receiving
elements) such as photodiodes, or thin film transistors
(TFT: Thin Film Transistor) are arranged in a matrix,
and the amount of pairs of electrons and positive holes
(the amount of charge) generated corresponding to the
25 amount of light entering the light receiving section of
each sensor is detected by a horizontal scanning
circuit and a vertical scanning circuit to thereby

detect the luminance of radiation.

In a photosensor system using such a CCD, it is usually necessary to respectively provide scanned photosensors with selective transistors for causing the 5 scanned photosensor to assume a selected state. In place of the combination of the photosensor and the selective transistor, a photosensor (hereinafter referred to as a "double-gate photosensor") is now being developed, which is formed of a thin film 10 transistor having a so-called double-gate structure and has both a photosensing function and a selecting function.

FIG. 16A is a sectional view illustrating the structure of such a double-gate photosensor 10. The 15 double-gate photosensor 10 comprises a semiconductor thin film 11 formed of amorphous silicon, n⁺-silicon layers 17 and 18, a source electrode 12 and a drain electrode 13 formed on the n⁺-silicon layers 17 and 18, respectively, a top gate electrode 21 formed above the 20 semiconductor thin film 11 with a block insulating film 14 and an upper gate insulating film 15 interposed therebetween, a protective insulating film 20 provided on the top gate electrode 21, and a bottom gate electrode 22 provided below the semiconductor thin film 11 with a lower gate insulating film 16 interposed 25 therebetween. The double-gate photosensor 10 is provided on a transparent insulating substrate 19

formed of, for example, glass.

In other words, the double-gate photosensor 10 includes an upper MOS transistor constituted of the semiconductor thin film 11, the source electrode 12, the drain electrode 13 and the top gate electrode 21, and a lower MOS transistor constituted of the semiconductor thin film 11, the source electrode 12, the drain electrode 13 and the bottom gate electrode 22.

As is indicated by the equivalent circuit of FIG. 16B, the double-gate photosensor 10 is considered to include two MOS transistors having a common channel region formed of the semiconductor thin film 11, TG (a Top Gate Terminal), BG (a Bottom Gate Terminal), S (a Source Terminal) and D (a Drain Terminal).

The protective insulating film 20, the top gate electrode 21, the upper gate insulating film 15, the block insulating film 14 and the lower gate insulating film 16 are all formed of a material having a high transmittance of visible light for activating the semiconductor thin film 11. Light entering the sensor from the top gate electrode 21 side passes through the top gate electrode 21, the upper gate insulating film 15 and the block insulating film 14, and then enters the semiconductor thin film 11, thereby generating and accumulating charges (positive holes) in the channel region.

FIG. 17 is a schematic view illustrating a

photosensor system formed of two-dimensionally arranged double-gate photosensors 10. As shown in FIG. 17, the photosensor system comprises a sensor array 100 that is constituted of a large number of double-gate
5 photosensors 10 arranged in a matrix of $(n \times m)$, top gate lines 101 that connect the top gate terminals TG of the double-gate photosensors 10 in a row direction, bottom gate lines 102 that connect the bottom gate terminals BG of the photosensors 10 in a row direction,
10 a top gate driver 111 and a bottom gate driver 112 connected to the top gate lines 101 and the bottom gate lines 102, respectively, data lines 103 that connect the drain terminals D of the double-gate photosensors 10 in a column direction, and an output circuit section
15 113 connected to the data lines 103.

In FIG. 17, ϕ_{tg} and ϕ_{bg} represent control signals for generating a reset pulse signal ϕ_{Ti} and a readout pulse signal ϕ_{Bi} , respectively, which will be described later, and ϕ_{pg} represents a pre-charge pulse signal for
20 controlling the point in time at which a pre-charge voltage V_{pg} is applied.

In the above-described structure, as described later, the photosensing function is realized by applying a predetermined voltage to the top gate terminals TG from the top gate driver 111, while
25 the readout function is realized by applying a predetermined voltage to the bottom gate terminals BG

from the bottom gate driver 112, then sending the output voltage of the photosensors 10 to the output circuit section 113 via the data lines 103, and outputting a serial data Vout.

5 FIGS. 18A - 18D are timing charts illustrating a method for drive-controlling the photosensor system, and indicating a detecting operation period (an i-th row processing cycle) at the i-th row of the sensor array 100. First, a high level pulse voltage (a reset pulse signal; $V_{tg} = + 15$ V, for example) ϕ_{Ti} as shown in FIG. 18A is applied to the top gate line 101 of the i-th row, and during a reset period T_{reset} , a resetting operation for discharging the double-gate photosensors 10 of the i-th row is executed.

10 15 Subsequently, a bias voltage ϕ_{Ti} of a low level (e.g. $V_{tg} = -15$ V) is applied to the top gate line 101 of the i-th row, thereby finishing the resetting period T_{reset} and starting a charge accumulating period T_a in which the channel region is charged. During the charge

20 accumulating period T_a , charge (positive holes) corresponding to the amount of light entering each sensor from the top gate electrode side are accumulated in the channel region.

25 Then, a pre-charge pulse signal ϕ_{pg} shown in FIG. 18C and having a pre-charge voltage V_{pg} is applied to the data lines 103 during the charge accumulating period T_a , and after a pre-charge period T_{prch} for

making the drain electrodes 13 keep a charge, a bias voltage (a readout pulse signal ϕ_{Bi}) of a high level (e.g. $V_{bg} = + 10$ V) shown in FIG. 18B is applied to the bottom gate line 102 of the i -th row. At this time, 5 the double-gate photosensors 10 of the i -th row are turned on to thereby start a readout period T_{read} .

During the readout period T_{read} , the charge accumulated in the channel region serves to moderate a low level voltage (e.g. $V_{tg} = -15$ V) of an opposite 10 polarity applied to each top gate terminal TG. Therefore, an n-type channel is formed by the voltage V_{bg} at each bottom gate terminal BG, whereby the voltage V_D at the data lines 103 gradually reduces, in accordance with the drain current, with lapse of time 15 after the pre-charge voltage V_{pg} is applied. More specifically, the tendency of change in the voltage V_D at the data lines 103 depends upon the charge accumulating period T_a and the amount of received light. As shown in FIG. 18D, the voltage V_D tends to gradually 20 reduce when the incident light is dark, i.e. a small amount of light is received, and hence only a small amount of charge is accumulated, whereas it tends to suddenly reduce when the incident light is bright, i.e. a large amount of light is received, and hence a large 25 amount of charge is accumulated. From this, it is understood that the amount of radiation can be calculated by detecting the voltage V_D at the data

lines 103 a predetermined period after the start of the readout period T_{read} , or by detecting a period required until the voltage VD reaches a predetermined threshold voltage.

5 Image reading is performed by sequentially executing the above-described drive-control for each line of the sensor array 100, by executing the control for each line in a parallel manner at different time points at which the driving pulses do not overlap.

10 Although the case of using the double-gate photosensor has been described above, even in a photosensor system using a photodiode or a phototransistor as a photosensor, sequential operations of "resetting operation → charge accumulating operation → 15 pre-charge operation → reading operation" are executed, and similar control is also executed.

The conventional photosensor systems as above have the following problems.

(1) In an image reading operation employed in 20 the above-described conventional photosensor system drive-control method, when using, for example, the above-described double-gate photosensor as a photosensor, a series of operations are repeated which include application of a reset pulse signal to the top 25 gate terminal TG , application of a pre-charge pulse signal to the drain terminal D and application of a readout pulse signal to the bottom gate terminal BG .

In this case, each pulse signal has a short pulse wave to be generated for a short time. For example, a high level voltage (e.g. + 15 V) is applied for a short time to the top gate terminal TG, and a low level voltage (e.g. -15 V) is applied thereto during the other period. Thus, during the operation period (e.g. the i-th row processing cycle shown in FIGS. 18A - 18D), the waveform of a voltage signal applied to the top gate terminal TG is asymmetrical with respect to 0 V (GND level). The effective voltage applied to the top gate terminal TG is V_{te} shown in FIG. 18A, which is greatly biased to the low level side (negative voltage side). Similarly, a high level voltage (e.g. + 10 V) is applied for a short time to the bottom gate terminal BG, and a low level voltage (GND level) is applied thereto during the other period. Thus, the waveform of a voltage signal applied to the bottom gate terminal TG is asymmetrical with respect to 0 V (GND level). The effective voltage applied to the bottom gate terminal BG is V_{be} shown in FIG. 18B, which is greatly biased to the high level side (positive voltage side).

If, in a photosensor having a thin film transistor structure, such a biased voltage is continuously applied to each gate terminal in a state in which light is applied to the sensor, for example, charge (positive holes or electrons) is trapped in each gate electrode, thereby degrading the element characteristics of the

photosensor and hence changing its sensitivity. As a result, the reliability of the photosensor reduces.

(2) Further, when a photosensor system using the aforementioned photosensors is used in various places or used to pick up images of various types of subjects, the subjects may have different brightnesses and these brightnesses may be varied depending upon the states of their environments. In order to accurately read images of various types of subjects in various environments, it is necessary to set the sensitivity of the photosensor to a value suitable for each subject and/or environment, and to read its image at the set sensitivity. The sensitivity of the photosensor is determined from, for example, the amount of charge accumulated within the charge accumulating period, i.e. corresponding to the total amount of incident light during the period. Accordingly, the sensitivity can be adjusted by adjusting the charge accumulating period. This being so, even when the effective voltage applied to each gate terminal is set at an optimal value, if the charge accumulating period is changed to a value appropriate for each environment, the effective voltage applied to each gate terminal will inevitably change and deviate from the optimal value. This changes, for example, the aforementioned sensitivity characteristic, thereby making it difficult to secure sufficient reliability of the image reading apparatus.

BRIEF SUMMARY OF THE INVENTION

It is an object of the invention to provide a highly reliable photosensor system having photosensors of a thin film transistor structure, wherein each 5 photosensor is free from significant degradation of its element characteristics and hence a great change in its sensitivity characteristic, which is caused when the effective voltage of a signal applied to each gate electrode of each photosensor is biased to a positive 10 or negative voltage side.

It is another object of the invention to prevent degradation of the element characteristics of each photosensor and to minimize the reduction of the 15 reliability of the photosensor system, even where an appropriate reading sensitivity is set for each photosensor in accordance with the environment of use, and a reading operation is executed at the set sensitivity.

To attain the objects, the invention provides a 20 photosensor system which comprises a photosensor array having a plurality of photosensors arranged two-dimensionally, a driver circuit and a readout circuit for applying signal voltages to each photosensor, a control circuit having a function of controlling the 25 voltages applied to each photosensor and adjusting the sensitivity of each photosensor, and a RAM storing data related to the control of the photosensor system.

The invention also provides a method for drive-controlling the photosensor system, characterized in that a correction signal, which has an effective voltage that can adjust an effective voltage, applied 5 to each gate electrode of each photosensor during the entire operation period, to 0 V, or to a value that minimizes degradation of the characteristics of each photosensor, is generated on the basis of a waveform obtained by reversing the polarity of a voltage signal 10 applied to each gate electrode of each photosensor during the resetting and reading operations executed for the photosensors in an image reading period, or by adjusting the timing of generation of a signal waveform. This correction signal is applied to each gate 15 electrode.

The method for drive-controlling the photosensor system is also characterized in that, even where a tentative image reading for determining an optimal sensitivity for each photosensor in accordance with the 20 environment of use is executed immediately before a regular reading operation for reading a subject image, thereby executing the regular reading operation at the determined optimal sensitivity, that correction signal is generated on the basis of a charge accumulating 25 period corresponding to the set optimal reading sensitivity, and applied to each gate electrode of each photosensor, which can adjust, to optimal values,

effective voltages applied to each gate electrode of each photosensor during the entire operation period, by offsetting effective voltages applied thereto during the tentative image reading operation for setting an 5 optimal sensitivity and during the regular image reading operation.

These control methods can correct, to an optimal value, a biased effective voltage applied to each gate electrode of each photosensor during the resetting and 10 reading operations, thereby minimizing degradation of the element characteristics of each photosensor and a change in its sensitivity characteristic caused by the degradation. As a result, a highly reliable photosensor system can be provided.

15 Additional objects and advantages of the invention will be set forth in the description which follows, and in part will be obvious from the description, or may be learned by practice of the invention. The objects and advantages of the invention may be realized and 20 obtained by means of the instrumentalities and combinations particularly pointed out hereinafter.

BRIEF DESCRIPTION OF THE SEVERAL VIEWS OF THE DRAWING

The accompanying drawings, which are incorporated in and constitute a part of the specification, 25 illustrate presently preferred embodiments of the invention, and together with the general description given above and the detailed description of the

preferred embodiments given below, serve to explain the principles of the invention.

FIG. 1 is a block diagram showing a photosensor system according to the invention;

5 FIGS. 2A - 2H are timing charts showing operation timing at each row employed in a photosensor control method according to a first embodiment of the invention;

10 FIGS. 3A and 3B are timing charts specifically illustrating the waveforms of voltage signals applied to the photosensor in the first embodiment;

15 FIGS. 4A - 4H are timing charts showing operation timing at each row employed in a photosensor control method according to a second embodiment of the invention;

FIGS. 5A and 5B are timing charts specifically illustrating the waveforms of voltage signals applied to the photosensor in the second embodiment;

20 FIGS. 6A - 6H are timing charts showing operation timing at each row employed in a photosensor control method according to a third embodiment of the invention;

25 FIGS. 7A and 7B are timing charts specifically illustrating the waveforms of voltage signals applied to the photosensor in the third embodiment;

FIG. 8 is a graph illustrating the relationship between each bias voltage applied to the gate electrode

of a transistor constituting a photosensor, the BT treatment temperature and the threshold voltage;

FIGS. 9A - 9H are timing charts showing operation timing at each row employed in a photosensor control method according to a fourth embodiment of the invention;

FIGS. 10A and 10B are timing charts specifically illustrating the waveforms of voltage signals applied to the photosensor in the fourth embodiment;

FIGS. 11A - 11H are timing charts showing operation timing at each row employed in a photosensor control method according to a fifth embodiment of the invention;

FIGS. 12A and 12B are timing charts specifically illustrating the waveforms of voltage signals applied to the photosensor in the fifth embodiment;

FIGS. 13A - 13H are timing charts showing operation timing at each row employed in a photosensor control method according to a sixth embodiment of the invention;

FIGS. 14A and 14B are conceptual diagrams showing the relationship between a signal applied to the photosensor of the sixth embodiment during an effective voltage adjusting operation period, and a signal applied to it during a pre-reading operation period and an image reading operation period;

FIGS. 15A - 15H are timing charts illustrating

another pre-reading operation executed in the sixth embodiment;

FIG. 16A is a sectional view showing the structure of a double-gate photosensor;

5 FIG. 16B is a diagram showing a circuit equivalent to the double-gate photosensor;

FIG. 17 is a diagram showing the circuit structure of the photosensor system in which double-gate photosensors are arranged two-dimensional; and

10 FIGS. 18A - 18D are timing charts showing a conventional method for controlling the double-gate photosensor system.

DETAILED DESCRIPTION OF THE INVENTION

Methods for controlling a photosensor system

15 according to the embodiments of the invention will be described in detail with reference to the accompanying drawings. Although in the embodiments described below, the double-gate photosensor having a thin film transistor structure is used as a photosensor, the invention is not limited to the double-gate photosensor, but also applicable to a photosensor system using another type of photosensor.

20 As is shown in FIG. 1, the photosensor system of the invention comprises a photosensor array 100 including double-gate photosensors 10, as shown in FIG. 16A, arranged two-dimensional; a top gate driver 111 for applying a predetermined reset pulse signal to

the top gate terminal TG of each double-gate
photosensor 10 at a predetermined point in time; a
bottom gate driver 112 for applying a predetermined
readout pulse signal to the bottom gate terminal BG of
5 each double-gate photosensor 10 at a predetermined
point in time; an output circuit section 113
constructed by a column switch 114 and a pre-charge
switch 115 for reading a data line voltage and applying
a pre-charge voltage to each double-gate photosensor 10,
10 respectively, a pre-charge switch 115 and an amplifier
116; an analog/digital converter (hereinafter referred
to as an "A/D converter") 117 for converting the read
data voltage as an analog signal into image data as a
digital signal; a controller 120 which is adapted to
15 control the operation of reading an image of a subject
by the photosensor array 100, to execute adjustment of
the effective voltage according to the invention, and
to exchange data with an external function section 200,
and which has a sensitivity setting function described
20 later; and a RAM 130 that stores, for example, read
image data, data related to setting of a reading
sensitivity described later or adjustment of the
effective voltage.

The structure including the photosensor array 100,
25 the top gate driver 111, the bottom gate driver 112 and
the output circuit section 113 is the same as and has
the same function as the conventional photosensor

system shown in FIG. 17. In addition to this structure, the photosensor system of the present invention also comprises the A/D converter 117, the controller 120 and the RAM 130, which enable various types of control as described below.

Specifically, the controller 120 outputs control signals ϕ_{tg} and ϕ_{bg} to the top gate driver 111 and the bottom gate driver 112, respectively, which, in turn, output predetermined signal voltages (a reset pulse signal ϕ_{Ti} and a readout pulse signal ϕ_{Bi}) to the top gate terminal TG and the bottom gate terminal BT of each double-gate photosensor 10 of the photosensor array 100, respectively. The controller also outputs a control signal ϕ_{pg} to the pre-charge switch 115, which, in turn, applies a pre-charge voltage V_{pg} to the data lines. As a result, an image of a subject is read. The data line voltage VD read from each double-gate photosensor 10 is converted into a digital signal via the amplifier 116 and the A/D converter 117, and supplied as image data to the controller 120. The controller 120 also has a function of executing predetermined image processing on the image data, writing or reading image data into or from the RAM 130. It serves as an interface for the external function section 200 that executes predetermined processing such as image data identification, modification, etc. The controller 120 has, as described later, another

function of controlling control signals ϕ_{tg} and ϕ_{bg} to be output to the top gate driver 111 and the bottom gate driver 112 to thereby adjust, to optimal values, the effective voltages applied to the top gate terminal 5 TG and the bottom gate terminal BG of each double-gate photosensor 10, and yet another function of setting an optimal reading sensitivity for reading an image of a subject in accordance with ambient illumination such as outside light, i.e. a function of setting an optimal 10 light accumulating period T_a for each double-gate photosensor 10.

Methods for controlling the photosensor system constructed as above will be described with reference to related figures including FIGS. 1 and 17 that show 15 the structure of the system.

As described below, in a photosensor system control method according to each embodiment, each operation is controlled on the basis of a control signal (ϕ_{tg} , ϕ_{bg} , ϕ_{pg} , etc.) supplied from the 20 controller 120.

<First Embodiment>

FIGS. 2A - 2H are timing charts illustrating operation timing at each row employed in the photo-sensor system control method of the first embodiment of 25 the invention. The first embodiment is directed to a case where the high and low levels of each of a reset pulse signal applied to each top gate line 101 and a

readout pulse signal applied to each bottom gate line 102 have opposite polarities (with respect to the GND level (0 V)) and the same absolute value.

In the control method of this embodiment, at first,
5 reset pulse signals $\phi T_1, \phi T_2, \dots, \phi T_n$ are sequentially applied to the top gate lines 101, thereby sequentially starting reset periods T_{reset} for respective rows and initializing the double-gate photosensors 10 at respective rows, as is shown in FIGS. 2A - 2C. The
10 reset pulse signals $\phi T_1, \phi T_2, \dots, \phi T_n$ each have a positive voltage (high level) V_{tgH} and a negative voltage (low level) V_{tgL} . The voltages V_{tgH} and V_{tgL} have shapes which have opposite polarities but symmetrical with respect to the GND level (0 V).

15 The reset pulses $\phi T_1, \phi T_2, \dots, \phi T_n$ sequentially fall to sequentially finish the reset periods T_{reset} and start respective light accumulating periods T_a , whereby charges (positive holes) are generated and accumulated in each channel region in accordance with
20 the amount of light entering the double-gate photosensors 10 at each row from their top gate electrode side. During the light accumulating period T_a , the pre-charge signal ϕ_{pg} is sequentially applied thereby to start the pre-charge period T_{prch} as shown
25 in FIG. 2G. As a result, the pre-charge voltage V_{prch} is applied to each data line 103, thereby executing a pre-charge operation for causing the drain electrode of

each double-gate photosensor 10 to keep a predetermined voltage.

After that, as shown in an image reading operation period shown in FIGS. 2D - 2F, readout pulse signals

5 $\phi B_1, \phi B_2, \dots \phi B_n$ are sequentially applied to those double-gate photosensors 10 via the bottom gate lines 102 of respective rows, at which the light accumulating period T_a and the pre-charge period T_{prch} have elapsed, thereby sequentially starting the readout periods T_{read} ,

10 sequentially reading a voltage change V_D , which corresponds to charges accumulated in each double-gate photosensor 10, from the output circuit section 113 via a corresponding data line 103, and sequentially storing the read voltage change in the RAM 130. The readout

15 pulse signals $\phi B_1, \phi B_2, \dots \phi B_n$ each have a positive voltage (high level) V_{bgH} and a negative voltage (low level) V_{bgL} . The voltages V_{bgH} and V_{bgL} have opposite polarities but symmetrical values with respect to the GND level (0 V).

20 The amount of radiation is calculated, as in the conventional case, by detecting the voltage V_D at the data lines 103 a predetermined period after the start of the readout period T_{read} , or by detecting a period required until the voltage V_D reaches a predetermined threshold voltage.

25 After the above-described series of image reading operations (the reset operation → the light

5 accumulating operation → the pre-charge operation → the readout operation) are executed for all rows of the photosensor array 100, a voltage, serving as a reverse bias with respect to the voltage applied to the top and bottom gate lines 101 and 102 of each row in the image reading operation, is applied to the top and bottom gate lines 101 and 102 of each row.

Specifically, in the reset operation executed during the effective voltage adjusting period shown in FIGS. 2A - 2C, a voltage signal of a waveform is generated, as a correction signal for each top gate line 101, which has a polarity opposite to that of the reset pulse signal $\phi T1$, $\phi T2$, \cdots ϕTn applied to the top gate terminal TG of each double-gate photosensor 10, i.e. a voltage signal of a waveform is generated which is obtained by inverting, with respect to the GND level (0 V), the waveform of a voltage signal applied to the top gate terminal TG of each double-gate photosensor 10 in the image reading period. The generated voltage signal is applied immediately before or after the image reading period (FIGS. 2A - 2C show cases where the signal application is executed immediately after the image reading period).

Similarly, in the readout operation executed
25 during the effective voltage adjusting period shown in
FIGS. 2D - 2F, a voltage signal of a waveform is
generated, as a correction signal for each bottom gate

line 102, which has a polarity opposite to that of the readout pulse signal $\phi B1$, $\phi B2$, \dots ϕBn applied to the bottom gate terminal BT of each double-gate photosensor 10, i.e. a voltage signal of a waveform is generated
5 which is obtained by inverting, with respect to the GND level (0 V), the waveform of a voltage signal applied to the bottom gate terminal BG of each double-gate photosensor 10 in the image reading period. The generated voltage signal is applied immediately before or after the image reading period (FIGS. 2D - 2F show
10 cases where the signal application is executed immediately after the image reading period).

A more detailed description will be given of the waveforms of the voltage signals applied to the top and
15 bottom gate terminals TG and BG of each double-gate photosensor 10.

FIGS. 3A and 3B are timing charts illustrating in detail the waveforms of the voltage signals applied to the top and bottom gate terminals TG and BG of each
20 double-gate photosensor 10 in this embodiment. Although these figures show only the waveforms of voltage signals applied to the top and bottom gate lines of a first row, similar voltage signals are applied to the gate lines of the other rows.

25 As is shown in FIG. 3A, when executing the reset operation during the image reading operation, a reset pulse signal $\phi T1$ of the positive voltage $VtgH$ is

applied for only a very short period (for the reset period T_{reset}) to the top gate terminal TG of each double-gate photosensor via corresponding top gate line 101. During a relatively long period other than the 5 reset period, a negative voltage V_{tgL} is applied thereto. Thus, the effective voltage applied to each top gate terminal TG is greatly biased to the negative voltage side.

On the other hand, also in the readout operation, 10 a readout pulse signal ϕ_{B1} of the positive voltage V_{bgH} is applied for only a very short period (for the readout period T_{read}) to the bottom gate terminal BG of each double-gate photosensor via a corresponding bottom gate line 102, as is shown in FIG. 3B. During a 15 relatively long period other than the readout period, a negative voltage V_{bgL} is applied thereto. Thus, the effective voltage applied to each bottom gate terminal BG is greatly biased to the negative voltage side. When a voltage signal having a waveform biased to one 20 polarity side is continuously applied to a gate terminal, charges (positive holes or electrons) are trapped in the gate section, thereby changing the sensitivity characteristic of the photosensors or degrading their element characteristics.

25 To avoid this, in this embodiment, a correction signal of a reversely biased waveform, which is obtained by inverting the polarity of the voltage

signal applied during the image reading period with respect to the GND level (0 V), is generated and applied to each gate electrode immediately before the image reading period or during the effective voltage 5 adjusting period immediately after the image reading period. In this control method for the photosensor system, voltage signals are applied to the top or bottom gate terminal TG or BG at a similar timing during the image reading period and the effective 10 voltage adjusting period, and have the same time integral value but opposite polarities. Accordingly, during the entire operation period including the image reading period and the effective voltage adjusting period, the voltage signals applied to the top or 15 bottom gate terminal TG or BG are offset to thereby eliminate the biased polarity of the effective voltage.

More specifically, suppose that, as shown in FIGS. 3A and 3B, the effective voltages applied to the top and bottom gate terminals TG and BG in the image 20 reading period are V_{te1} and V_{be1} , respectively, and the effective voltages applied to the top and bottom gate terminals TG and BG in the effective voltage adjusting period are V_{te2} and V_{be2} , respectively. In this case, the effective voltages applied to the terminals during 25 both the periods have the same absolute value and different polarities, and $|V_{te1}| = |V_{te2}|$ and $|V_{be1}| = |V_{be2}|$ are established. Accordingly, the average

voltages (average effective voltages) V_{te} and V_{be} applied to the top and bottom gate terminals TG and BG during the entire operation period including the image reading period and the effective voltage adjusting period are 0 V since the effective voltages applied to the top or bottom gate terminals TG or BG in both the periods are offset. As a result, accumulation of charges (positive holes or electrons) in the gate section is prevented, and hence degradation of the element characteristics or the sensitivity characteristic of each photosensor can be minimized.

Further in the embodiment, during the image reading operation and the effective voltage adjusting period, voltages necessary for a signal to be applied to each top gate terminal TG are a pair of positive and negative voltages V_{tgH} and V_{tgL} ($= -V_{tgH}$), which have opposite polarities with respect to the GND level (0 V). Similarly, voltages necessary for a signal to be applied to each bottom gate terminal BG are a pair of positive and negative voltages V_{bgH} and V_{bgL} ($= -V_{bgH}$), which have opposite polarities with respect to the GND level (0 V). Accordingly, each of the top gate driver 111 and the bottom gate driver 112 can be formed of a driver of a two-value output. Since this type of driver is cheap, the photosensor system using such drivers can be made at a low cost.

<Second Embodiment>

A method for controlling a photosensitive system according to a second embodiment of the invention will be described with reference to FIGS. 4A - 5B.

5 This embodiment differs from the first embodiment in that, in the former, the reset pulse signal and the readout pulse signal used in the image reading period each have a high level voltage and a low level voltage which are asymmetrical with respect to the GND level
10 (0 V).

FIGS. 4A - 4H are timing charts illustrating operation timing at each row employed in the photosensor system control method of the second embodiment of the invention. FIGS. 5A and 5B are
15 timing charts illustrating in detail the waveforms of the voltage signals applied to the top and bottom gate terminals TG and BG of each double-gate photosensor 10 in this embodiment. The same control as employed in the above-described first embodiment will not be
20 described in detail.

In the control method of this embodiment, at first, reset pulse signals $\phi T1$, $\phi T2$, \cdots ϕTn shown in FIGS. 4A - 4C are sequentially applied to the top gate lines 101, thereby sequentially starting reset periods
25 Treset for respective rows, initializing the double-gate photosensors 10 at the respective rows, and starting respective light accumulating periods Ta. As

a result, charges (positive holes) corresponding to the amount of incident light are accumulated in each channel region. Each of the reset pulse signals $\phi T1$, $\phi T2$, \dots ϕTn has a positive voltage (high level) $VtgH2$ 5 and a negative voltage (low level) $VtgL1$ ($\neq -VtgH2$), which are asymmetrical with respect to the GND level (0 V).

After that, readout pulse signals $\phi B1$, $\phi B2$, \dots ϕBn as shown in FIGS. 4D - 4F are sequentially applied 10 to those double-gate photosensors 10 via the bottom gate lines 102 of respective rows, at which the light accumulating period Ta and the pre-charge period $Tprch$ have passed, thereby sequentially starting readout 15 periods $Tread$, sequentially reading a voltage change VD shown in FIG. 4H, which corresponds to charges accumulated in each double-gate photosensor 10, from the output circuit section 113 via a corresponding data line 103, and sequentially storing the read voltage change in the RAM 130. The readout pulse signals $\phi B1$, 20 $\phi B2$, \dots ϕBn each have a positive voltage (high level) $VbgH2$ and a negative voltage (low level) $VbgL1$ that are asymmetrical with respect to the GND level (0 V).

After the above-described series of image reading operations are executed for all rows of the photosensor 25 array 100, correction signals, serving as reverse bias signals with respect to voltage signals applied to the top and bottom gate lines 101 and 102 of each row

5 during the image reading operation, are applied to the top and bottom gate lines 101 and 102 of each row for a period identical to the period required for the image reading operation at all rows during the effective
10 voltage adjusting period immediately after the image reading period. Alternatively, this signal application may be executed immediately before the image reading period.

10 More specifically, as shown in FIGS. 5A and 5B, a correction signal, which is created by inverting the polarity of a voltage signal applied to each top gate terminal TG during the image reading period with respect to the GND level (0 V), and which has a positive voltage V_{tgH1} ($= -V_{tgL1}$) as a high level
15 voltage and a negative voltage V_{tgL2} ($= -V_{tgH2}$) as a low voltage, is applied to each top gate terminal TG during the effective voltage adjusting period. On the other hand, a correction signal, which is created by inverting the polarity of a voltage signal applied to
20 each bottom gate terminal BG during the image reading period with respect to the GND level (0 V), and which has a positive voltage V_{bgH1} ($= -V_{bgL1}$) as a high level voltage and a negative voltage V_{bgL2} ($= -V_{bgH2}$) as a low voltage, is applied to each bottom gate terminal BG
25 during the effective voltage adjusting period.

 In this control method for the photosensor system, voltage signals are applied to the top or bottom gate

terminal TG or BG at a similar timing during the image reading period and the effective voltage adjusting period, and have the same time integral value but opposite polarities. Accordingly, during the entire 5 operation period including the image reading period and the effective voltage adjusting period, the average voltages V_{te} and V_{be} applied to the top and bottom gate terminals TG and BG are 0 V, thereby preventing accumulation of charge (positive holes or electrons) in 10 each gate electrode, and hence minimizing a change in the sensitivity characteristic of the photosensors or degradation of their element characteristics.

Since in this embodiment, the high level and low level voltages of each of the reset pulse signal and 15 the readout pulse signal used during the image reading period are asymmetrical with respect to the GND level (0 V), voltages necessary for a signal to be applied to each of the top and bottom gate terminals TG and BG during the image reading period and the effective 20 voltage adjusting period are two positive voltages and two negative voltages, i.e. four voltages in total, which are asymmetrical with respect to the GND level (0 V). Accordingly, each of the top and bottom gate drivers 111 and 112 can be formed of a driver of a 25 multi-level output. This enables application of an appropriate voltage for the sensitivity characteristic of each photosensor, and hence enables an appropriate

image reading operation.

<Third Embodiment>

A method for controlling a photosensitive system according to a third embodiment of the invention will 5 be described with reference to FIGS. 6A - 7B.

This embodiment is directed to a case similar to the second embodiment, where the reset pulse signal and the readout pulse signal used in the image reading period each have a high level voltage and a low level 10 voltage which are asymmetrical with respect to the GND level (0 V).

FIGS. 6A - 6H are timing charts illustrating operation timing at each row employed in the photo-sensor system control method of the third embodiment of 15 the invention. FIGS. 7A and 7B are timing charts illustrating in detail the waveforms of the voltage signals applied to the top and bottom gate terminals TG and BG of each double-gate photosensor 10 in this embodiment. The same control as employed in the above-20 described embodiments will not be described in detail.

In the control method of this embodiment, at first, reset pulse signals $\phi T1$, $\phi T2$, \dots ϕTn shown in FIGS. 6A - 6C are sequentially applied to the top gate lines 101, thereby sequentially starting reset periods 25 Treset for respective rows, initializing the double-gate photosensors 10 at the respective rows, and starting respective light accumulating periods Ta. As

a result, charges (positive holes) corresponding to the amount of incident light are accumulated in each channel region. Each of the reset pulse signals $\phi T1$, $\phi T2$, \dots ϕTn has a positive voltage (high level) $VtgH$ 5 and a negative voltage (low level) $VtgL$ ($\neq -VtgH$), which are asymmetrical with respect to the GND level (0 V).

After that, readout pulse signals $\phi B1$, $\phi B2$, \dots ϕBn as shown in FIGS. 6D - 6F are sequentially applied 10 to those double-gate photosensors 10 via the bottom gate lines 102 of respective rows, at which the light accumulating period Ta and the pre-charge period $Tprch$ have passed, thereby sequentially starting readout 15 periods $Tread$, sequentially reading a voltage change VD shown in FIG. 6H, which corresponds to charges accumulated in each double-gate photosensor 10, from the output circuit section 113 via a corresponding data line 103, and sequentially storing the read voltage change in the RAM 130. The readout pulse signals $\phi B1$, 20 $\phi B2$, \dots ϕBn each have a positive voltage (high level) $VbgH$ and a negative voltage (low level) $VbgL$ ($\neq -VbgH$) that are asymmetrical with respect to the GND level (0 V).

After the above-described series of image reading 25 operations are executed for all rows of the photosensor array 100, correction signals having reverse bias voltage waveforms that offset, to thereby make them 0 V,

the effective voltages applied to the top and bottom gate lines 101 and 102 of each row in the image reading operation, are applied to the top and bottom gate lines 101 and 102 of each row during the effective voltage 5 adjusting period immediately after the image reading period. Alternatively, this signal application may be executed immediately before the image reading period.

Specifically, during the effective voltage adjusting period, a correction signal is generated and 10 applied to each top gate terminal TG, which has the same positive and negative voltages V_{tgH} and V_{tgL} as the pulse signal applied thereto during the image reading period, and has an effective voltage V_{te2} ($= -V_{te1}$) created by adjusting the signal widths of the 15 positive and negative voltages V_{tgH} and V_{tgL} and inverting, with respect to the GND level (0 V), the polarity of an effective voltage V_{te1} applied thereto during the image reading period. Further, during the effective voltage adjusting period, a correction signal 20 is generated and applied to each bottom gate terminal BG, which has the same positive and negative voltages V_{bgH} and V_{bgL} as the pulse signal applied thereto during the image reading period, and has an effective voltage V_{be2} ($= -V_{be1}$) created by adjusting the signal widths of the positive and negative voltages V_{bgH} and 25 V_{bgL} and inverting, with respect to the GND level (0 V), the polarity of an effective voltage V_{be1} applied

thereto during the image reading period.

More specifically, as shown in FIGS. 7A and 7B, during the effective voltage adjusting period, a correction signal is generated and applied to each top 5 gate terminal TG, which has a positive voltage (high level) V_{tgH} and a negative voltage (low level) V_{tgL} , and has an effective voltage V_{te2} created by inverting, with respect to the GND level (0 V), the polarity of an effective voltage V_{tel} applied thereto during the image 10 reading period. Further, during the effective voltage adjusting period, a correction signal is generated and applied to each bottom gate terminal BG, which has a positive voltage (high level) V_{bgH} and a negative voltage (low level) V_{bgL} , and has an effective voltage 15 V_{be2} created by inverting, with respect to the GND level (0 V), the polarity of an effective voltage V_{bel} applied thereto during the image reading period. The effective voltage adjusting period may be identical to the period required for the image reading operation, or 20 may be different from it, i.e. may be shorter than the period. In other words, it is sufficient if voltage signals are set such that the effective voltages applied to the top and bottom gate terminals TG and BG during the effective voltage adjusting period offset 25 the effective voltages applied thereto during the image reading period.

In the above-described control method for the

photosensor system, during the entire operation period including the image reading period and the effective voltage adjusting period, the average effective voltages V_{te} and V_{be} applied to the top and bottom gate terminals TG and BG are 0 V (GND level), thereby preventing accumulation of charges (positive holes or electrons) in the gate section is prevented, and suppressing degradation of the element characteristics or the sensitivity characteristic of each photosensor.

Further in this embodiment, during the image reading operation and the effective voltage adjusting period, voltages necessary for each signal to be applied to the top and bottom gate lines 101 and 102 during the image reading period and the effective voltage adjusting period are a pair of positive and negative voltages, which have opposite polarities and are asymmetrical with respect to the GND level (0 V). Accordingly, each of the top gate driver 111 and the bottom gate driver 112 can be formed of a driver of a two-value output. Since this type of driver is cheap, the photosensor system using such drivers can be made at a low cost.

<Fourth Embodiment>

A method for controlling a photosensitive system according to a fourth embodiment of the invention will be described with reference to FIGS. 8 - 10B.

This embodiment is directed to a case similar to

the second embodiment, where the reset pulse signal and the readout pulse signal used in the image reading period each have a high level voltage and a low level voltage which are asymmetrical with respect to the GND
5 level (0 V). However, the fourth embodiment is characterized in that a reverse bias voltage waveform is set so as to minimize a change in the threshold value of a transistor that constitutes a photosensor.

10 FIG. 8 shows the relationship between each bias voltage applied to the gate electrode of a transistor constituting a photosensor, the BT treatment temperature and the threshold voltage of the transistor. Changes in the threshold value after the BT treatment were measured by the CV measurement method.

15 In the examples shown in FIG. 8, the threshold voltage greatly changes from several volts to ten and several volts when a positive bias is applied to the gate electrode, while it slightly changes within a range of several volts or less when a negative bias is
20 applied thereto. Accordingly, where the effective voltage applied to the gate electrode is 0 V, and the positive bias and the negative bias are applied for the same period, the sensitivity characteristic of the double-gate photosensor may change or its element
25 characteristics may degrade since, as described above, the threshold voltage more greatly changes when the positive bias is applied, than when the negative bias

is applied. Therefore, to reduce a change in the threshold voltage, it is preferable that the effective voltage applied to the gate electrode is biased to the negative voltage side. As aforementioned, in this 5 embodiment, the effective voltage applied to the gate electrode is set at a value, other than 0 V, which minimizes a change in the threshold voltage. A reverse bias voltage signal created for this end is applied to each gate terminal immediately before or after the 10 image reading period.

In the case of FIG. 8, the threshold voltage more greatly changes when the positive bias is applied, than when the negative bias is applied. However, this is just an example, and there is an opposite case where 15 the threshold voltage more greatly changes when the negative bias is applied to the gate electrode. This difference depends upon the element structure, the used material, etc.

FIGS. 9A - 9H are timing charts illustrating 20 operation timing at each row employed in the photosensor system control method of the fourth embodiment of the invention. FIGS. 10A and 10B are timing charts illustrating in detail the waveforms of the voltage signals applied to the top and bottom gate terminals TG and BG of each double-gate photosensor in 25 this embodiment. Like the second embodiment, the fourth embodiment is also directed to a case where the

reset pulse signal and the readout pulse signal used in the image reading period each have a high level voltage and a low level voltage which are asymmetrical with respect to the GND level (0 V). The same control as 5 employed in the above-described embodiments will not be described in detail.

In the control method of this embodiment, at first, 10 reset pulse signals $\phi T1, \phi T2, \dots \phi Tn$ shown in FIGS. 9A - 9C are sequentially applied to the top gate lines 101, thereby sequentially starting reset periods T_{reset} , initializing the double-gate photosensors 10 at respective rows, and starting respective light accumulating periods Ta . As a result, charge (positive holes) corresponding to the amount of incident light is 15 accumulated in each channel region. Each of the reset pulse signals $\phi T1, \phi T2, \dots \phi Tn$ has a positive voltage (high level) V_{tgH2} and a negative voltage (low level) $V_{tgL1} (\neq -V_{tgH2})$, which are asymmetrical with respect to the GND level (0 V).

20 After that, readout pulse signals $\phi B1, \phi B2, \dots \phi Bn$ as shown in FIGS. 9D - 9F are sequentially applied to those double-gate photosensors 10 via the bottom gate lines 102 of respective rows, at which the light accumulating period Ta and the pre-charge period T_{prch} 25 have passed, thereby sequentially starting readout periods T_{read} , sequentially reading a voltage change VD shown in FIG. 9H, which corresponds to charges

5 accumulated in each double-gate photosensor 10, from the output circuit section 113 via a corresponding data line 103, and sequentially storing the read voltage change in the RAM 130. The readout pulse signals $\phi B1$, $\phi B2$, \dots ϕBn each have a positive voltage (high level) $VbgH2$ and a negative voltage (low level) $VbgL1$ ($\neq -VbgH2$) that are asymmetrical with respect to the GND level (0 V).

10 After the above-described series of image reading operations are executed for all rows of the photosensor array, correction signals having reverse bias voltage waveforms that offset and minimize a change in the threshold voltage of each transistor, which occurs depending upon the polarities of voltages applied to 15 the top and bottom gate lines 101 and 102 of each row in the image reading operation, are applied to the top and bottom gate lines 101 and 102 of each row during the effective voltage adjusting period immediately after the image reading period. Alternatively, this 20 signal application may be executed immediately before the image reading period.

25 Specifically, during the effective voltage adjusting period, a correction signal is generated and applied to each top gate terminal TG, which is obtained by inverting the polarity of a voltage signal applied thereto during the image reading period, with respect to an optimal voltage Vte set so as to minimize, or to

make 0, a change in the threshold value of a top gate terminal TG side transistor of each double-gate photosensor 10, and which has a positive voltage V_{tgH1} (high level) and a negative voltage V_{tgL2} (low level).

5 Further, during the effective voltage adjusting period, a correction signal is generated and applied to each bottom gate terminal BG, which is obtained by inverting the polarity of a voltage signal applied thereto during the image reading period, with respect to an optimal voltage V_{be} set so as to minimize a change in the threshold value of a bottom gate terminal BG side transistor of each double-gate photosensor 10, and which has a positive voltage (high level) V_{bgH1} and a negative voltage (low level) V_{bgL2} .

10 More specifically, as shown in FIGS. 10A and 10B, the effective voltages V_{te2} and V_{be2} of reverse bias voltage signals used during the effective voltage adjusting period are set on the basis of the effective voltages V_{te1} and V_{be1} applied to respective gate electrodes during the image reading period, so that optimal voltages V_{te} and V_{be} , which minimize, or make 0, a change in the threshold value of each transistor of each photosensor, can be obtained as average effective voltages during the entire process period including the 15 image reading period and the effective voltage adjusting period. In other words, the reverse bias voltage signals are set so that the average values of

the effective voltages V_{tel} and V_{bel} applied during the image reading period, and the effective voltages V_{te2} and V_{be2} applied during the effective voltage adjusting period are identical to the optimal voltages V_{te} and V_{be} , respectively.

In the above-described control method for the photosensor system, reverse bias voltage signals are applied to the top gate terminal TG and the bottom gate terminal BG so that the average effective voltages during the entire process period including the image reading period and the effective voltage adjusting period can minimize, or make 0, a change in the threshold voltage of each transistor. Accordingly, the invention can provide a highly reliable photosensor system that can suppress the influence of a change in the threshold voltage of each transistor due to the polarities of voltages applied to the top and bottom gate terminals TG and BG, and hence can minimize degradation of the sensitivity characteristic or the element characteristics of each photosensor.

In this embodiment, voltages necessary for a signal to be applied to each of the top and bottom gate terminals TG and BG during the image reading period and the effective voltage adjusting period are two positive voltages and two negative voltages, i.e. four voltages in total, which are asymmetrical with respect to the GND level (0 V). Accordingly, each of the top and

bottom gate drivers 111 and 112 can be formed of a driver of a multi-level output. This enables application of an appropriate voltage for the sensitivity characteristic of each photosensor, and
5 hence enables an appropriate image reading operation.

<Fifth Embodiment>

A method for controlling a photosensitive system according to a fifth embodiment of the invention will be described with reference to FIGS. 11A - 12B.

10 This embodiment is directed to a case similar to the fourth embodiment, where the reset pulse signal and the readout pulse signal used in the image reading period each have a high level voltage and a low level voltage which are asymmetrical with respect to the GND
15 level (0 V), and is characterized in that a reverse bias voltage waveform is set so as to minimize a change in the threshold value of a transistor that constitutes a photosensor.

FIGS. 11A - 11H are timing charts illustrating
20 operation timing at each row employed in the photosensor system control method of the fifth embodiment of the invention. FIGS. 12A and 12B are timing charts illustrating in detail the waveforms of the voltage signals applied to the top and bottom gate terminals TG and BG of each double-gate photosensor in
25 this embodiment. The same control as employed in the above-described embodiments will not be described in

detail.

In the control method of this embodiment, at first, reset pulse signals ϕT_1 , ϕT_2 , \dots ϕT_n shown in FIGS. 11A - 11C are sequentially applied to the top gate lines 101, thereby sequentially starting reset periods T_{reset} for respective rows, initializing the double-gate photosensors 10 at the respective rows, and starting respective light accumulating periods T_a . As a result, charges (positive holes) corresponding to the amount of incident light are accumulated in each channel region. Each of the reset pulse signals ϕT_1 , ϕT_2 , \dots ϕT_n has a positive voltage (high level) V_{tgH} and a negative voltage (low level) V_{tgL} ($\neq -V_{tgH}$), which are asymmetrical with respect to the GND level (0 V).

After that, readout pulse signals ϕB_1 , ϕB_2 , \dots ϕB_n as shown in FIGS. 11D - 11F are sequentially applied to those double-gate photosensors 10 via the bottom gate lines 102 of respective rows, at which the light accumulating period T_a and the pre-charge period T_{prch} have passed, thereby sequentially starting readout periods T_{read} , sequentially reading a voltage change V_D shown in FIG. 11H, which corresponds to charges accumulated in each double-gate photosensor 10, from the output circuit section 113 via a corresponding data line 103, and sequentially storing the read voltage change in the RAM 130. The readout pulse

signals $\phi B1$, $\phi B2$, \dots ϕBn each have a positive voltage (high level) $VbgH2$ and a negative voltage (low level) $VbgL1$ ($\neq -VbgH2$) that are asymmetrical with respect to the GND level (0 V).

5 After the above-described series of image reading operations are executed for all rows of the photosensor array, correction signals having reverse bias voltage waveforms that offset and minimize a change in the threshold voltage of each transistor, which occurs
10 depending upon the polarities of voltages applied to the top and bottom gate lines 101 and 102 of each row in the image reading operation, are applied to the top and bottom gate lines 101 and 102 of each row during the effective voltage adjusting period immediately
15 after the image reading period. Alternatively, this signal application may be executed immediately before the image reading period.

Specifically, during the effective voltage adjusting period, a correction signal is generated and
20 applied to each top gate terminal TG, which is obtained by inverting the polarity of a voltage signal applied thereto during the image reading period, with respect to an optimal voltage Vte set so as to minimize, or to make 0, a change in the threshold value of a top gate terminal TG side transistor of each double-gate
25 photosensor 10, and which has a positive voltage (high level) $VtgH$ and a negative voltage (low level) $VtgL$,

the widths of the positive voltage and negative voltage signal components being adjusted. Further, during the effective voltage adjusting period, a correction signal is generated and applied to each bottom gate terminal 5 BG, which is obtained by inverting the polarity of a voltage signal applied thereto during the image reading period, with respect to an optimal voltage V_{be} set so as to minimize a change in the threshold value of a bottom gate terminal BG side transistor of each double- 10 gate photosensor 10, and which has a positive voltage (high level) V_{bgH} and a negative voltage (low level) V_{bgL} , the widths of the positive voltage and negative voltage signal components being adjusted.

More specifically, as shown in FIGS. 12A and 12B, 15 the effective voltages V_{te2} and V_{be2} of reverse bias voltage signals used during the effective voltage adjusting period are set on the basis of the effective voltages V_{tel} and V_{bel} applied to each gate electrode during the image reading period, so that optimal 20 voltages V_{te} and V_{be} , which minimize, or make 0, a change in the threshold value of each transistor of each photosensor, can be obtained as average effective voltages during the entire process period including the image reading period and the effective voltage adjusting period. In other words, the reverse bias voltage signals are set so that the average voltages of 25 the effective voltages V_{tel} and V_{bel} applied during the

image reading period, and the effective voltages V_{te2} and V_{be2} applied during the effective voltage adjusting period are identical to the optimal voltages V_{te} and V_{be} , respectively.

5 The effective voltage adjusting period may be identical to the period required for the image reading operation, or may be different from it, i.e. may be shorter than the period. In other words, it is sufficient if voltage signals are set such that the
10 effective voltages applied to the top and bottom gate terminals TG and BG during the effective voltage adjusting period are identical to the average effective voltages V_{te} and V_{be} .

15 In the above-described control method for the photosensor system, reverse bias voltage signals are applied to the top gate terminal TG and the bottom gate terminal BG so that the average effective voltages during the entire process period including the image reading period and the effective voltage adjusting
20 period can minimize, or make 0, a change in the threshold voltage of each transistor. Accordingly, the invention can provide a highly reliable photosensor system that can suppress the influence of a change in the threshold voltage of each transistor due to the
25 polarities of voltages applied to the top and bottom gate terminals TG and BG, and hence can minimize degradation of the sensitivity characteristic or the

element characteristics of each photosensor.

In this embodiment, voltages necessary for a signal to be applied to each of the top and bottom gate terminals TG and BG during the image reading period and the effective voltage adjusting period are a pair of positive and negative voltages that are asymmetrical with respect to the GND level (0 V). Accordingly, each of the top and bottom gate drivers 111 and 112 can be formed of a driver of a two-value output. Since this type of driver is cheap, the photosensor system using such drivers can be made at a low cost.

<Sixth Embodiment>

A method for controlling a photosensitive system according to a sixth embodiment of the invention will be described with reference to FIGS. 13A - 14B.

This embodiment is directed to a control method that includes, in addition to the step of reading an image of a subject as described in the first to fifth embodiments, the step of executing, immediately before the image reading period, an operation (hereinafter referred to as a "pre-reading operation") for determining an optimal sensitivity for the photosensor, which varies in accordance with various conditions such as the brightness of the environment, the type of a to-be-detected subject, etc., and is used for the image reading operation.

FIGS. 13A - 13H are timing charts illustrating

operation timing at each row employed in the photosensor system control method of the sixth embodiment of the invention. The same control as employed in the above-described embodiments will not be 5 described in detail. In this embodiment, the high and low level voltages of voltage signals applied to the top and bottom gate lines 101 and 102 are asymmetrical with respect to the GND level (0 V), and reverse bias voltage waveforms are set so that a change in the 10 threshold voltage of a transistor constituting a photosensor can be minimized, as in the fourth and fifth embodiments.

When executing the pre-reading operation in this embodiment, at first, reset pulse signals ϕT_1 , ϕT_2 , \dots 15 ϕT_n shown in FIGS. 13A - 13C are sequentially applied to the top gate lines 101 with regular delay periods T_{DELAY} , thereby sequentially starting reset periods T_{RESET} for respective rows and initializing the double-gate photosensors 10 at the respective rows. 20 Each of the reset pulse signals ϕT_1 , ϕT_2 , \dots ϕT_n has a positive voltage (high level) V_{TGH} and a negative voltage (low level) V_{TGL} ($\neq -V_{TGH}$), which are asymmetrical with respect to the GND level (0 V).

The reset pulses ϕT_1 , ϕT_2 , \dots ϕT_n sequentially fall to thereby sequentially finish the reset periods T_{RESET} and start respective light accumulating periods T_{A1} , T_{A2} , \dots T_{An} . As a result, charges (positive holes)

corresponding to the amount of light entering the double-gate photosensors 10 of each row from their gate electrode side are accumulated in the channel regions of the photosensors. After a pre-charge signal ϕ_{pg} shown in FIG. 13G is applied so that the light accumulating period $TA_1, TA_2, \dots TA_n$ set for each row will vary in a stepwise manner in units of the predetermined delay period T_{DELAY} after the last reset pulse ϕ_{Tn} falls. Further, readout pulse signals $\phi_{B1}, \phi_{B2}, \dots \phi_{Bn}$ as shown in FIGS. 13D - 13F are sequentially applied to the bottom gate lines 102, thereby sequentially starting readout periods T_{read} , sequentially reading a voltage change VD shown in FIG. 13H, which corresponds to charge accumulated in each double-gate photosensor 10, from the output circuit section 113 via a corresponding data line 103, and sequentially storing the read voltage change in the RAM 130.

The readout pulse signals $\phi_{B1}, \phi_{B2}, \dots \phi_{Bn}$ each have a positive voltage (high level) V_{bgH} and a negative voltage (low level) $V_{bgL} (\neq -V_{bgH})$ that are asymmetrical with respect to the GND level (0 V).

Since, in the above-described pre-reading operation, the light accumulating period $TA_1, TA_2, \dots TA_n$ set for each row varies in units of as twice a period as the predetermined delay period T_{DELAY} , image data can be obtained which is read at a reading

5 sensitivity set with a sensitivity adjusting width
greater than the number of rows of the photosensor
array 100. On the basis of this image data, the
controller 120 extracts, for example, a light
10 accumulating period that enables a maximum contrast of
light and shade, and determines an optimal light
accumulating period T_a . The method for determining the
optimal light accumulating period T_a from image data is
not limited to the above method for extracting
15 conditions that enable the maximum contrast.

After the pre-reading operation, an image reading
operation is executed using the optimal light
accumulating period T_a determined by the pre-reading
operation. This image reading operation is basically
15 the same as that executed in the first to fifth
embodiments.

Specifically, at first, reset pulse signals ϕT_1 ,
 ϕT_2 , \dots ϕT_n are sequentially applied to the top gate
lines 101, thereby sequentially starting reset periods
20 T_{reset} for respective rows and initializing the double-
gate photosensors 10 at respective rows. These reset
pulse signals ϕT_1 , ϕT_2 , \dots ϕT_n each have, like the
reset pulse signals used in the pre-reading operation,
a positive voltage (high level) V_{tgH} and a negative
25 voltage (low level) V_{tgL} ($\neq -V_{tgH}$) that are
asymmetrical with respect to the GND level (0 V).

The reset pulses ϕT_1 , ϕT_2 , \dots ϕT_n sequentially

fall to sequentially finish the reset periods T_{reset} and start the aforementioned optimal light accumulating periods T_a for respective rows, whereby charges (positive holes) are generated and accumulated in the 5 channel region of each double-gate photosensor 10 in accordance with the amount of light entering it from its top gate electrode side.

After that, readout pulse signals $\phi B_1, \phi B_2, \dots \phi B_n$ are sequentially applied to those double-gate 10 photosensors 10 via the bottom gate lines 102 of respective rows, at which the optimal light accumulating period T_a and the pre-charge period T_{prch} have elapsed, thereby sequentially starting readout 15 periods T_{read} , sequentially reading a voltage change V_D , which corresponds to charge accumulated in each double-gate photosensor 10, from the output circuit section 113 via a corresponding data line 103, and sequentially storing the read voltage change in the RAM 130.

These readout pulse signals $\phi B_1, \phi B_2, \dots \phi B_n$ each 20 have, like the readout pulse signals used in the pre-reading operation, a positive voltage (high level) V_{bgH} and a negative voltage (low level) $V_{bgL} (\neq -V_{bgH})$ that are asymmetrical with respect to the GND level (0 V).

After the image reading operation is executed for 25 all rows, an effective voltage adjusting operation is executed during the effective voltage adjusting period for adjusting and optimizing the biased effective

voltage signal applied to each gate line during the pre-reading operation and the image reading operation.

Specifically, during the effective voltage adjusting period, those correction signals are

5 generated and applied to the top and bottom gate lines 101 and 102 of each row, which have effective voltages that can adjust the average values of the effective voltages applied thereto as reset pulse signals during the pre-reading period and the image reading period, 10 and the effective voltages applied thereto during the effective voltage adjusting period, to optimal voltages V_{te} and V_{be} that minimize, or make 0, a change in the threshold value of each transistor of each photosensor.

The signals applied to each top gate terminal TG and each bottom gate terminal BG during the effective

15 voltage adjusting period will be described in more detail with reference to related figures. For facilitate the description, suppose that both the effective voltage applied to each top gate terminal TG 20 and the effective voltage applied to each bottom gate terminal BG are biased to the low-level side, and the description is related only to the top and bottom gate lines of the first row.

FIGS. 14A and 14B show the relationship, employed 25 in the method for controlling the photosensor system according to this embodiment, between signals applied to each top gate terminal TG and each bottom gate

terminal during the effective voltage adjusting period, and signals applied thereto during the pre-reading period and the image reading period.

As is shown in FIGS. 13A - 13H, in the reset 5 operation during the pre-reading period and the image reading period, a reset pulse signal $\phi T1$ of a high level voltage (positive voltage) $VtgH$ is applied for only a very short period (for the reset period T_{reset}) to each top gate terminal TG via a corresponding top gate line 101. During a relatively long period other than the reset period, a low level voltage (negative voltage) $VtgL$ is applied thereto. The light accumulating period Ta employed in the image reading operation is set during the pre-reading period in 10 accordance with, for example, the illuminance of the environment.

15

On the other hand, also in the readout operation during the pre-reading period and the image reading period, a readout pulse signal $\phi B1$ of a high level voltage (positive voltage) $VbgH$ is applied for only a very short period (for the readout period T_{read}) to each bottom gate terminal BG via a corresponding bottom gate line 102. During a relatively long period other than the readout period, a low level voltage (negative voltage) $VbgL$ is applied thereto. The light accumulating period Ta employed in the image reading operation is set during the pre-reading period in 20 25

accordance with, for example, the illumination of the environment.

In this embodiment, signals are generated, which have voltage waveforms that can make the absolute value of the high-level-side time integral value of the waveforms of voltages applied to each gate terminal of each photosensor during the pre-reading period, the image reading period and the period of the effective voltage adjusting operation to be executed, equal to the absolute value of the low-level-side time integral value of them, with reference to the optimal effective voltage V_{te} applied to each top gate terminal TG and the optimal effective voltage V_{be} applied to each bottom gate terminal BG, which are set in accordance with the sensitivity characteristic of the double-gate photosensor. These generated signals are applied to each top gate line 101 and each bottom gate line 102 for the double-gate photosensors at predetermined time points during the effective voltage adjusting period.

As is shown in FIGS. 13A - 13C, the correction signal applied to each top gate line 101 during the effective voltage adjusting period includes a low-level-side voltage component having a predetermined signal width (indicating a period in time) T_{TPL} , and a high-level-side voltage component having a predetermined signal width T_{TPH} , with respect to the optimal effective voltage V_{te} for each top gate

terminal TG.

On the other hand, the correction signal applied to each bottom gate line 102 during the effective voltage adjusting period includes a low-level-side voltage component having predetermined signal widths T_{BPLA} and T_{BPLB} , and a high-level-side voltage component having a predetermined signal width T_{BPH} , with respect to the optimal effective voltage V_{be} for each bottom gate terminal BG.

The relationship between the correction signal applied to each top gate terminal TG and the other signal is shown in FIG. 14A. Suppose that, in FIG. 14A, V_{te} represents the optimal effective voltage of each top gate terminal TG, V_{tgH} a high voltage contained in a signal applied thereto during the pre-reading period and the image reading period, V_{tgL} a low voltage contained in the signal, T_a the optimal light accumulating period employed during the image reading operation, T_{LT} a low level period other than the optimal light accumulating period during the pre-reading period and the image reading period, and T_{HT} a high level period (i.e. $T_{RESET} + T_{RESET}$) during the pre-reading period and the image reading period. Then, the following equation is given:

$H_t \cdot (T_{TPH} + T_{HT}) = L_t \cdot (T_a + T_{LT} + T_{TPL}) \quad \dots(1)$
where H_t represents the absolute value ($|V_{tgH} - V_{te}|$) of the difference between the high voltage V_{tgH} and

the optimal voltage V_{te} , and L_t the absolute value ($|V_{tgL} - V_{te}|$) of the difference between the low voltage V_{tgL} and the optimal voltage V_{te} .

From the equation (1), the relationship between
5 the application period of the correction signal for
each top gate line 101 during the effective voltage
adjusting period, i.e. the relationship between the
signal width T_{TPH} of the high-level-side voltage
component and the signal width T_{TPL} of the low-level-
10 side voltage component is given by

$$T_{TPH} = L_t/H_t \cdot (T_a + T_{LT} + T_{TPL}) - T_{HT} \quad \dots (2)$$

Accordingly, even when the optimal light
15 accumulating period during the image reading operation
is changed in accordance with the illumination of the
environment, if a signal of the high voltage V_{tgH} is
applied to each top gate line 101 for a period
20 corresponding to T_{TPH} expressed by the equation (2),
the biased effective voltage applied to each top
gate terminal TG can be adjusted to the optimal
value V_{te} , thereby minimizing a change in the
sensitivity characteristic of each double-gate
photosensor due to degradation of its element
characteristics.

On the other hand, the relationship between the
25 correction signal applied to each bottom gate line 102
and the other signal is shown in FIG. 14B. Suppose
that, in FIG. 14B, V_{be} represents the optimal effective

voltage of each bottom gate terminal BG, V_{bgH} a high voltage contained in a signal applied thereto during the pre-reading period and the image reading period, V_{bgL} a low voltage contained in the signal, T_a the 5 optimal light accumulating period employed during the image reading operation, T_{LB} a low level period other than the optimal light accumulating period T_a during pre-reading period and the image reading period, and T_{HB} a high level period (i.e. $T_{READ} + T_{READ}$) during the 10 pre-reading period and the image reading period. Then, the following equation is given:

$Hb \cdot (T_{BPH} + T_{HB}) = Lb \cdot (T_a + T_{LB} + T_{BPL}) \quad \dots (3)$
where Hb represents the absolute value ($|V_{bgH} - V_{be}|$) 15 of the difference between the high voltage V_{bgH} and the optimal voltage V_{be} , and Lb the absolute value ($|V_{bgL} - V_{be}|$) of the difference between the low voltage V_{bgL} and the optimal voltage V_{be} . Further, T_{BPL} represents the total signal width ($T_{BPLA} + T_{BPLB}$) of the low-level-side voltage components.

20 From the equation (3), the relationship between the application period of the correction signal for each bottom gate line 102, i.e. the relationship between the signal width T_{BPH} of the high-level-side voltage component and the signal width T_{BPL} of the low-25 level-side voltage components is given by

$$T_{BPH} = Lb/Hb \cdot (T_a + T_{LB} + T_{BPL}) - T_{HB} \quad \dots (4)$$

Accordingly, even when the optimal light

5 accumulating period T_a during the image reading operation is changed in accordance with the illumination of the environment, if a signal of the high voltage V_{tgH} is applied to each bottom gate line 102 for a period corresponding to T_{BPH} expressed by the equation (2), the biased effective voltage applied to each bottom gate terminal BG can be adjusted to the optimal value V_{te} , thereby minimizing a change in the sensitivity characteristic of each double-gate 10 photosensor due to degradation of its element characteristics.

15 The optimal effective voltages V_{te} and V_{be} , set for each top gate terminal TG and each bottom gate terminal BG, respectively, during the above-described effective voltage adjusting operation in accordance with the sensitivity characteristic of the double-gate photosensors, are determined from the element structure of the double-gate photosensors or materials used for them, and can be positive voltages, negative voltages
20 or 0 V.

Moreover, in this embodiment, the high-level-side voltage component and the low-level-side voltage component of the correction signal applied to each top or bottom gate terminal TG or BG during the effective voltage adjusting operation are identical to corresponding voltage components of the voltage signal applied thereto during the pre-reading operation and

the image reading operation. In this case, two voltages are applied to each of the top and bottom gate terminals TG and BG, and hence each of the top gate driver 111 and the bottom gate driver 112 can be formed of a driver of a two-value output, as in the first, third and fifth embodiments. Since this type of driver is cheap, the photosensor system using such drivers can be made at a low cost. However, the sixth embodiment is not limited to this structure. It may be modified like the second and fourth embodiments such that a signal applied to each top or bottom gate terminal TG or BG during the image reading period and the effective voltage adjusting period has different high level voltages and low level voltages, and hence each of the top and bottom gate drivers 111 and 112 can be formed of a driver of a multi-level output.

Further, in the sixth embodiment, the manner of executing the pre-reading operation is not limited to that shown in FIGS. 13A - 13H, but may be modified.

FIGS. 15A - 15H are timing charts illustrating another pre-reading operation that can be employed in the sixth embodiment.

In this pre-reading operation, at first, reset pulse signals ϕT_1 , ϕT_2 , \dots ϕT_n as shown in FIGS. 15A - 15C are simultaneously applied to all top gate lines 101, thereby starting a reset period T_{reset} for all rows and simultaneously initializing the double-gate

photosensors 10 of all rows.

The reset pulses $\phi T_1, \phi T_2, \dots \phi T_n$ simultaneously fall to finish the reset period T_{reset} and simultaneously start light accumulating periods $TB_1, TB_2, \dots TB_n$ for the double-gate photosensors 10 of all rows, whereby charge (positive holes) is generated and accumulated in each channel region in accordance with the amount of light entering the double-gate photosensors 10 of each row from their top gate electrode side.

A pre-charge signal ϕ_{pg} as shown in FIG. 15G is applied so as to make the light accumulating periods $TB_1, TB_2, \dots TB_n$, set for respective rows, longer by respectively increasing delay periods T_{DELAY} , and readout pulse signals $\phi B_1, \phi B_2, \dots \phi B_n$ are sequentially applied to the bottom gate lines 102 as shown in FIGS. 15D - 15F, thereby sequentially starting readout periods T_{read} , sequentially reading voltage changes $VD_1, VD_2, VD_3, \dots VD_m$, which correspond to charge accumulated in the double-gate photosensors 10 of respective rows, from the output circuit section 113 via the respective data lines 103, and sequentially storing the read voltage change in the RAM 130.

Accordingly, image data read with different reading sensitivities set for the respective rows of an image of a subject can be obtained by reading the subject image only one time.

The manner of executing the pre-reading operation used in this embodiment is not limited to the above-described one. It is sufficient if an image of a subject can be read with different reading 5 sensitivities. For example, a series of operations -- a reset operation → a light accumulating operation → a pre-charge operation → a reading operation -- may be repeated several times while sequentially changing the reading sensitivity to obtain image data using 10 different reading sensitivities. Any other appropriate method may be, of course, employed.

Although, in the above-described embodiments, the double-gate photosensor is used as a photosensor, the invention is not limited to this. The control method 15 of the invention is applicable to a photosensor system using another type of photosensors, if their sensitivity characteristic or element characteristics are liable to change or degrade because the voltage polarity of a signal applied during a pre-reading 20 operation or an image reading operation, and such a change or degradation can be minimized by a correction signal applied during an effective voltage adjusting operation.

Although in the above-described embodiments, a 25 pulse signal having an opposite voltage polarity is applied during the effective voltage adjusting operation in accordance with the operation

characteristics of a double-gate photosensor or the structure of the photosensor system, the invention is not limited to this. If the average effective voltage during the entire period including the pre-reading period and the image reading period can be set at a value (0 V or a predetermined value) at which a change in the photosensor characteristics can be suppressed, a signal having a predetermined voltage may be applied instead of a pulse signal having an opposite voltage polarity.

Additional advantages and modifications will readily occur to those skilled in the art. Therefore, the invention in its broader aspects is not limited to the specific details and representative embodiments shown and described herein. Accordingly, various modifications may be made without departing from the spirit or scope of the general inventive concept as defined by the appended claims and their equivalents.

WHAT IS CLAIMED IS:

1. A photosensor system comprising:

a photosensor array including a plurality of
photosensors arranged two-dimensionally;

5 initializing means for applying a reset pulse
signal to each of the photosensors of the photosensor
array, thereby initializing the photosensors;

10 signal readout means for applying a pre-charge
pulse signal to each of the photosensors of the
photosensor array, applying a readout pulse signal to
each of the photosensors, and receiving a voltage
output from each of the photosensors; and

15 effective voltage adjusting means for applying, to
each of the photosensors, correction signals for
correcting, to optimal values, effective voltages of
the signals applied to each of the photosensors by the
initializing means and the signal readout means.

20 2. The photosensor system according to claim 1,
further comprising optimal reading sensitivity setting
means for reading, using the signal readout means, a
subject image formed of pixels corresponding to the
photosensors arranged two-dimensionally while changing
an image reading sensitivity set for each of the
photosensors by the initializing means and the signal
readout means, thereby determining an optimal image
25 reading sensitivity on the basis of image patterns of
the subject image formed with respective set reading

sensitivities.

3. The photosensor system according to claim 1,
wherein the correction signals applied by the effective
voltage adjusting means set, at 0 V, average effective
5 voltages of the signals applied to the photosensors by
the initializing means and the signal readout means.

4. The photosensor system according to claim 1,
wherein the correction signals applied by the effective
voltage adjusting means adjust average effective
10 voltages of signals, applied to each of the
photosensors by the initializing means and the signal
readout means, to values at which a change in a
threshold voltage of each of the photosensors is
minimized.

15 5. The photosensor system according to claim 1,
wherein voltage waveforms of the correction signals
applied by the effective voltage adjusting means have
time integral values of polarities opposite to those of
time integral values of voltage waveforms of the
20 signals applied to each of the photosensors by the
initializing means and the signal readout means.

6. The photosensor system according to claim 1,
wherein each of signals, applied to each of the
photosensors by the initializing means and the
25 effective voltage adjusting means and by the signal
readout means and the effective voltage adjusting means,
has a pair of high-level and low-level voltages.

7. The photosensor system according to claim 1,
wherein each of signals, applied to each of the
photosensors by the initializing means and the
effective voltage adjusting means and by the signal
5 readout means and the effective voltage adjusting means,
has pairs of high-level and low-level voltages.

8. The photosensor system according to claim 1,
wherein:

each of the photosensors has a double-gate
10 structure including a source electrode and a drain
electrode formed with a semiconductor layer as a
channel region interposed therebetween, and a top gate
electrode and a bottom gate electrode formed above and
below the channel region with respective insulating
15 films interposed therebetween; and

the initializing means initializes each of the
photosensors by applying the reset pulse signal to the
top gate electrode of each of the photosensors, and the
signal readout means applies the readout pulse signal
20 to the bottom gate electrode of each of the
photosensors, thereby outputting, as the output voltage,
a voltage corresponding to charge accumulated in the
channel region during a charge accumulating period
ranging from termination of the initialization to
25 application of the readout pulse signal.

9. A method of controlling a photosensor system
including a photosensor array having a plurality of

photosensors arranged two-dimensionally, comprising:

an initializing step of applying a reset pulse signal to each of the photosensors of the photosensor array, thereby initializing the photosensors;

5 a signal readout step of applying a pre-charge pulse signal to each of the photosensors of the photosensor array, applying a readout pulse signal to each of the photosensors, and receiving a voltage output from each of the photosensors; and

10 an effective voltage adjusting step of adjusting, to predetermined optimal values, effective voltages of the signals applied to each of the photosensors in the initializing and signal readout steps.

15 10. The method according to claim 9, wherein the optimal values of the effective voltages of the signals applied to the photosensors, adjusted in the effective voltage adjusting step, are 0 V.

20 11. The method according to claim 9, wherein the optimal values of the effective voltages of the signals applied to the photosensors, adjusted in the effective voltage adjusting step, are values at which a change in a threshold voltage of each of the photosensors is minimized.

25 12. The method according to claim 9, wherein: each of the photosensors has a double-gate structure including a source electrode and a drain electrode formed with a semiconductor layer as a

channel region interposed therebetween, and a top gate electrode and a bottom gate electrode formed above and below the channel region with respective insulating films interposed therebetween; and

5 the initializing means initializes each of the photosensors by applying the reset pulse signal to the top gate electrode of each of the photosensors, and the signal readout means applies the readout pulse signal to the bottom gate electrode of each of the

10 photosensors, thereby outputting, as the output voltage, a voltage corresponding to charge accumulated in the channel region during a charge accumulating period ranging from termination of the initialization to application of the readout pulse signal.

15 13. The method according to claim 9, further comprising:

 a pre-reading step of reading a subject image formed of pixels corresponding to the photosensors of the photosensor array arranged two-dimensionally, while 20 changing an image reading sensitivity set for each of the photosensors in the initializing step and the signal readout step, thereby setting an optimal image reading sensitivity on the basis of image patterns of the subject image obtained while changing the image 25 reading sensitivity;

 an image reading step of reading an entire portion of the subject image using the set optimal image

reading sensitivity; and

an effective voltage adjusting step of adjusting, to the optimal values, the effective voltages of the signals applied to each of the photosensors of the 5 photosensor array during the pre-reading step and the image reading step.

14. The method according to claim 13, wherein the pre-reading step includes:

a first step of applying a first reset pulse 10 signal, having a predetermined polarity, to each of the photosensors in a first time period, thereby initializing the photosensors, a first signal voltage being applied during a period other than the first time period; and

15 a second step of applying, after the initialization, a first readout pulse signal, having a predetermined polarity, to each of the photosensors in a second time period, at which a pre-charge operation based on the pre-charge pulse signal has been finished,

20 thereby outputting a first readout voltage corresponding to charge accumulated during a charge accumulating period ranging from termination of the initialization to application of the first readout pulse signal, a second signal voltage being applied during a period other than the second time period; and

25 the first readout pulse signal is applied in the second time period such that it changes the charge

5 accumulating period at a predetermined ratio, and an optimal charge accumulating period is determined on the basis of an image pattern of the subject image obtained from the first readout voltage corresponding to charge accumulated in each charge accumulating period.

15. The method according to claim 14, wherein
the image reading step includes:
a third step of applying a second reset pulse
signal, having a predetermined polarity, to each of the
photosensors in a third time period, thereby
initializing the photosensors, a third signal voltage
being applied during a period other than the third time
period; and
a fourth step of applying, after the
initialization, a second readout pulse signal, having a
predetermined polarity, to each of the photosensors at
which a pre-charge operation based on the pre-charge
pulse signal has been finished, in a fourth time period
corresponding to the optimal charge accumulating period
determined during the pre-reading step, thereby
outputting a second readout voltage corresponding to
charge accumulated during the optimal charge
accumulating period ranging from termination of the
initialization to application of the second readout
pulse signal, a fourth signal voltage, being applied
during a period other than the fourth time period, and
the effective voltage adjusting step includes:

a fifth step of applying, to each of the photosensors, a fifth signal having a predetermined effective voltage for adjusting, to the optimal value, an effective voltage applied to each of the

5 photosensors and based on the first and second reset pulse signals and the first and third signal voltages applied in the first and third steps; and

a sixth step of applying, to each of the photosensors, a sixth signal having a predetermined effective voltage for adjusting, to the optimal value, an effective voltage applied to each of the photosensors and based on the first and second readout pulse signals and the second and fourth signal voltages applied in the second and fourth steps.

10 15 16. The method according to claim 15, wherein: the fifth signal is created with reference to the optimal effective voltage set in accordance with a sensitivity characteristic of each of the photosensors and has an effective voltage with a polarity opposite to the effective voltage applied to each of the photosensors and based on the first and second reset pulse signals and the first and third signal voltages applied in the first and third steps; and

20 25 the sixth signal is created with reference to the optimal effective voltage set in accordance with the sensitivity characteristic of each of the photosensors and has an effective voltage with a polarity opposite

to the effective voltage applied to each of the photosensors and based on the first and second readout pulse signals and the second and fourth signal voltages applied in the second and fourth steps.

5 17. The method according to claim 15, wherein:
 in the fifth step, the fifth signal is applied to each of the photosensors, which has a fifth voltage component lower than the optimal effective voltage set in accordance with the sensitivity characteristic of each of the photosensors, and a sixth voltage component higher than the optimal effective voltage, the fifth and sixth voltage components having their time widths set to predetermined values at which an absolute value of a time integral value of the first and third signal voltages and the fifth voltage component is equal to an absolute value of a time integral value of the first and second reset pulse signals and the sixth voltage component; and

20 15 25 in the sixth step, the sixth signal is applied to each of the photosensors, which has a seventh voltage component lower than the optimal effective voltage set in accordance with the sensitivity characteristic of each of the photosensors, and an eighth voltage component higher than the optimal effective voltage, the seventh and eighth voltage components having their time widths set to predetermined values at which an absolute value of a time integral value of the second

and fourth signal voltages and the seventh voltage component is equal to an absolute value of a time integral value of the first and second readout pulse signals and the eighth voltage component.

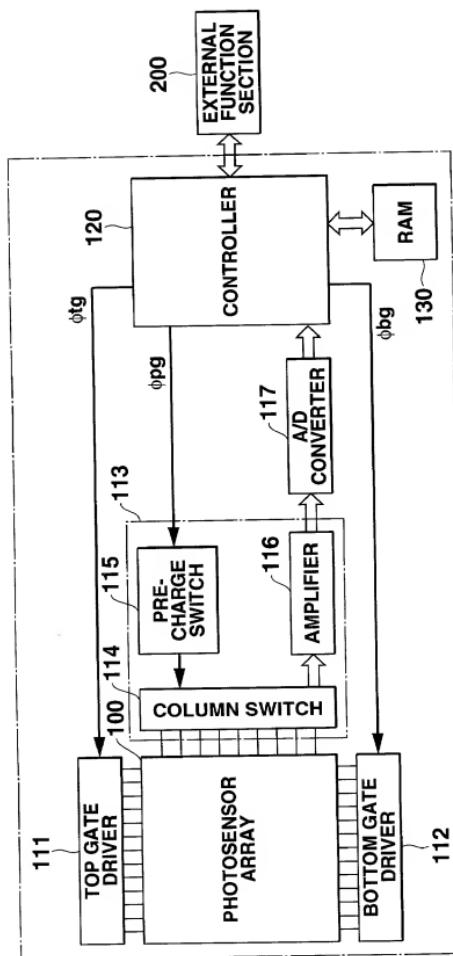
5 18. The method according to claim 15, wherein voltage waveforms of the signals applied to each of the photosensors in the first, third and fifth steps, and voltage waveforms of the signals applied to each of the photosensors in the second, fourth and sixth steps are
10 generated by two-value drivers each for generating a pair of low-level and high-level voltages.

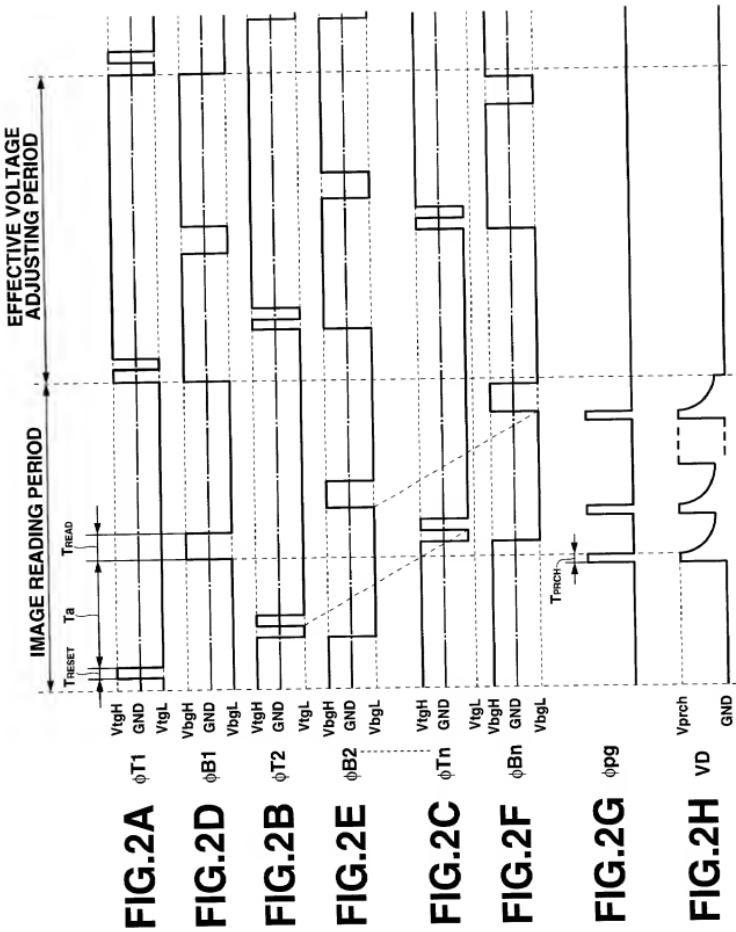
15 19. The method according to claim 15, wherein voltage waveforms of the signals applied to each of the photosensors in the first, third and fifth steps, and voltage waveforms of the signals applied to each of the photosensors in the second, fourth and sixth steps are generated by multi-level drivers each for generating pairs of low-level and high-level voltages.

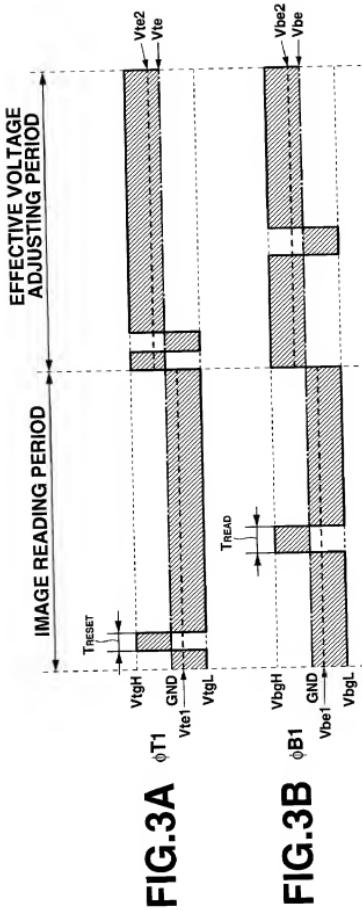
ABSTRACT OF THE DISCLOSURE

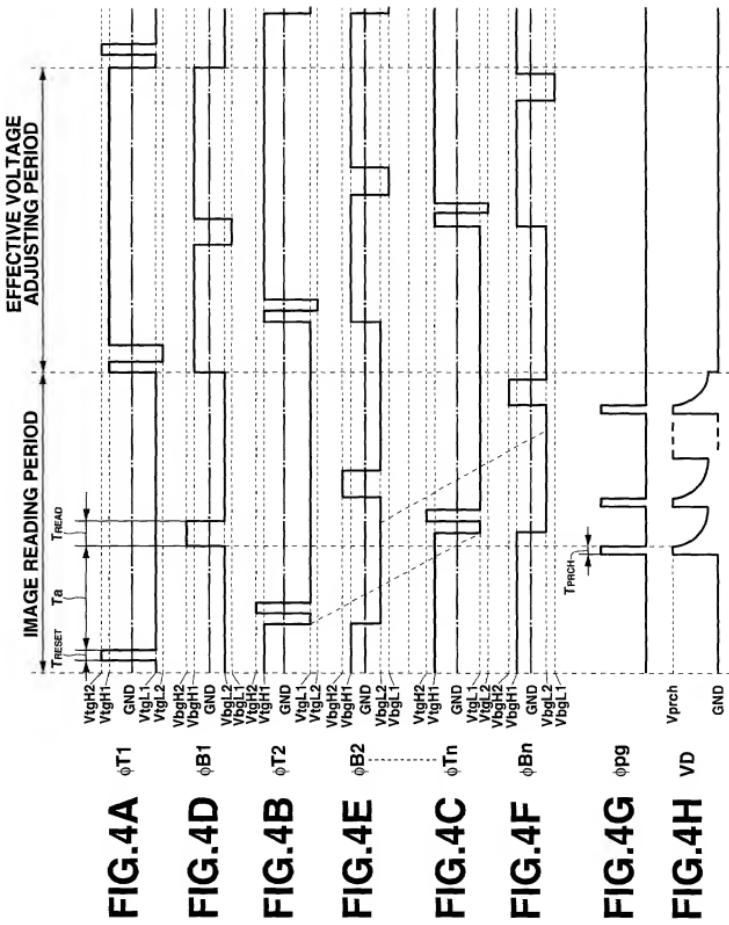
A photosensor system including a photosensor array having a plurality of photosensors arranged two-dimensionally comprises a driver circuit and a readout circuit for applying signal voltages to each photosensor, and also a control circuit having a function of controlling the voltages applied to each photosensor and adjusting the sensitivity of each photosensor. During an image reading operation and a reading operation for setting the sensitivity of each photosensor, a correction signal is generated, which has an effective voltage that can adjust an effective voltage, applied to each gate electrode of each photosensor, to 0 V, or to a value that minimizes degradation of the characteristics of each photosensor. This correction signal is applied to each gate electrode.

FIG.1









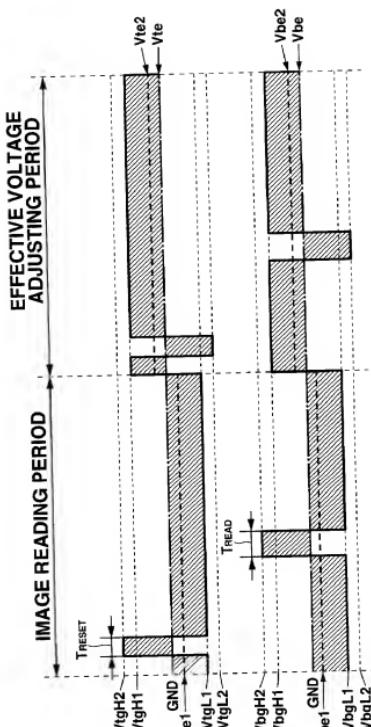
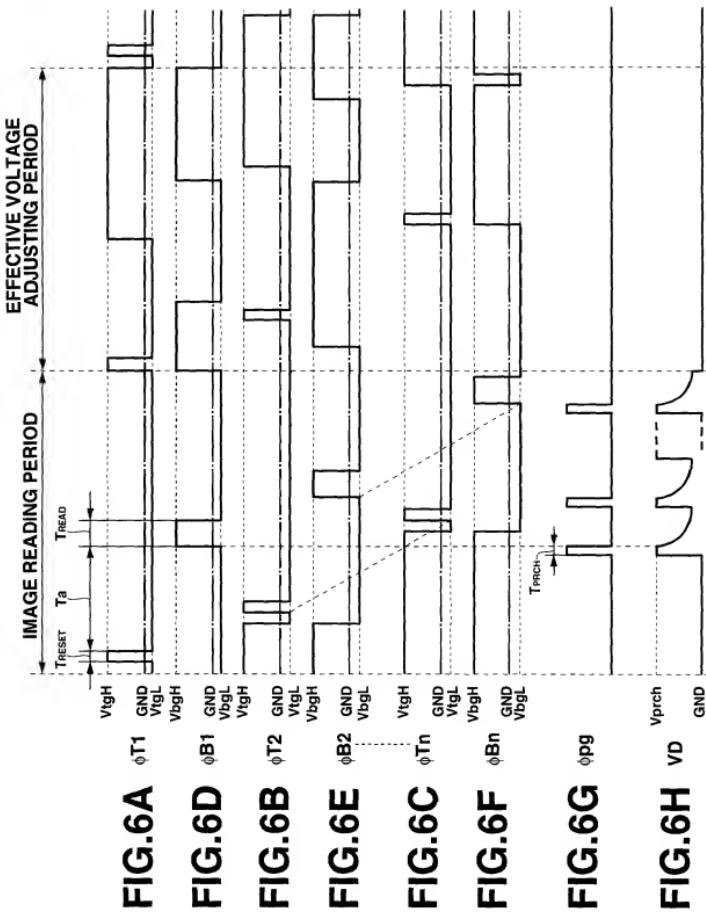


FIG.5A

FIG.5B



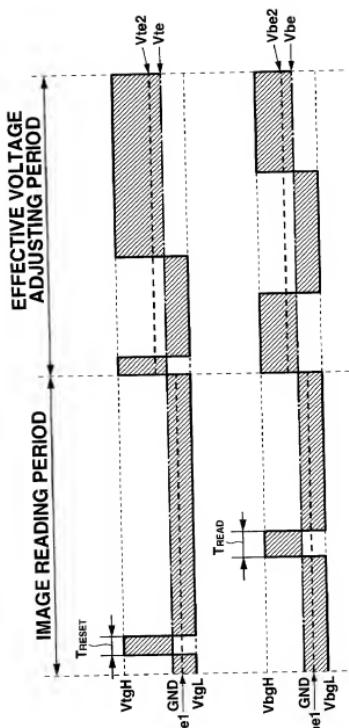
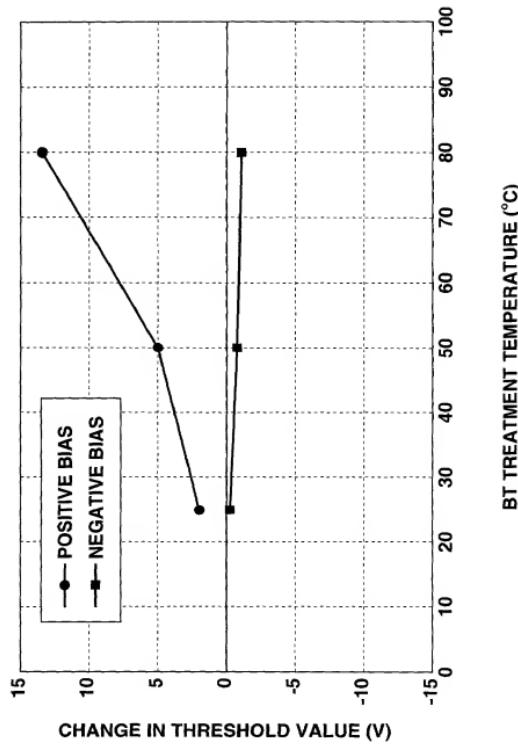
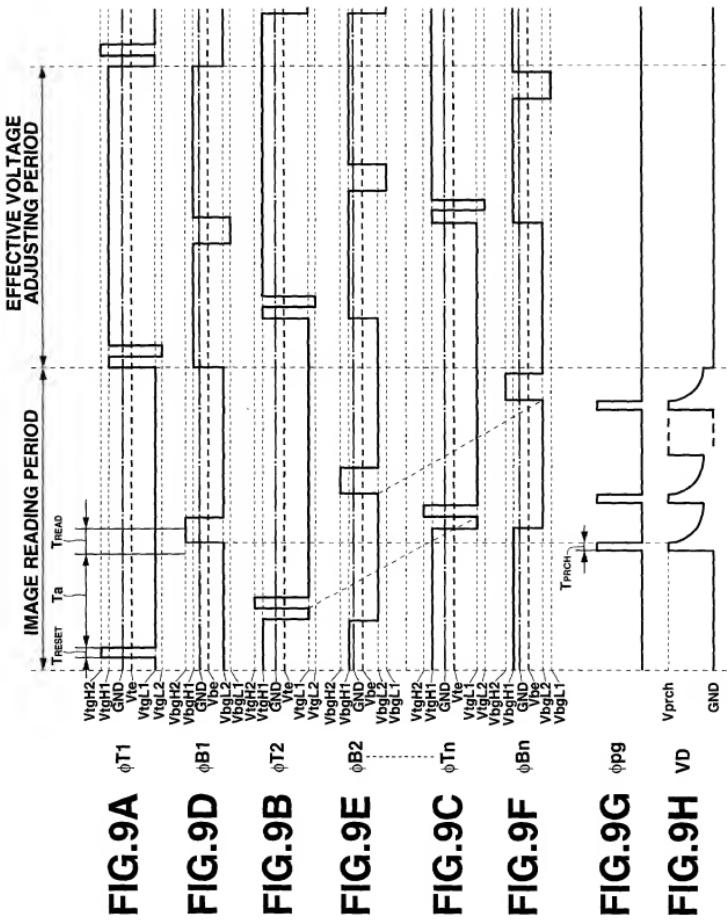
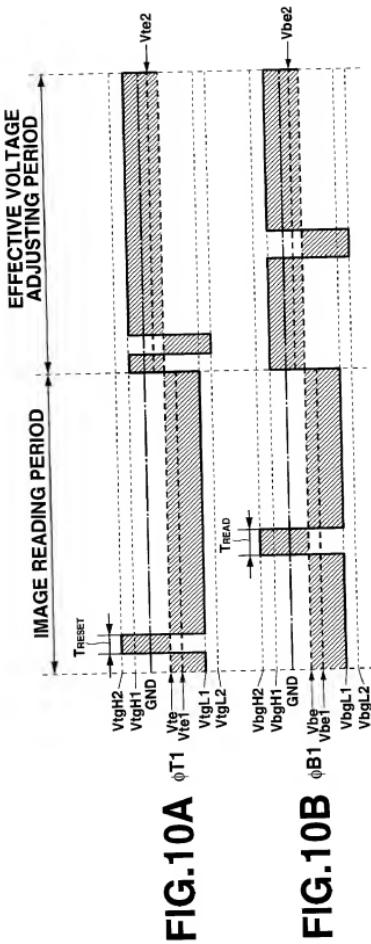
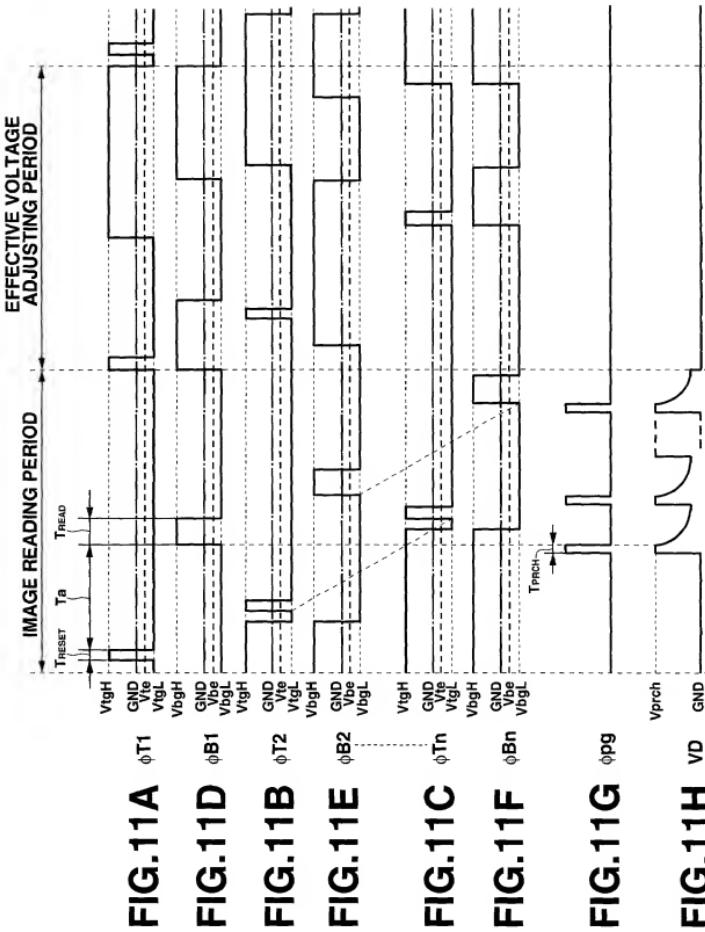


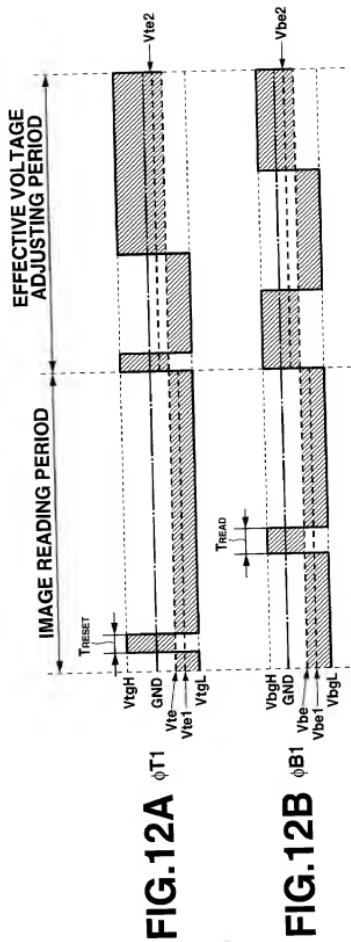
FIG.8

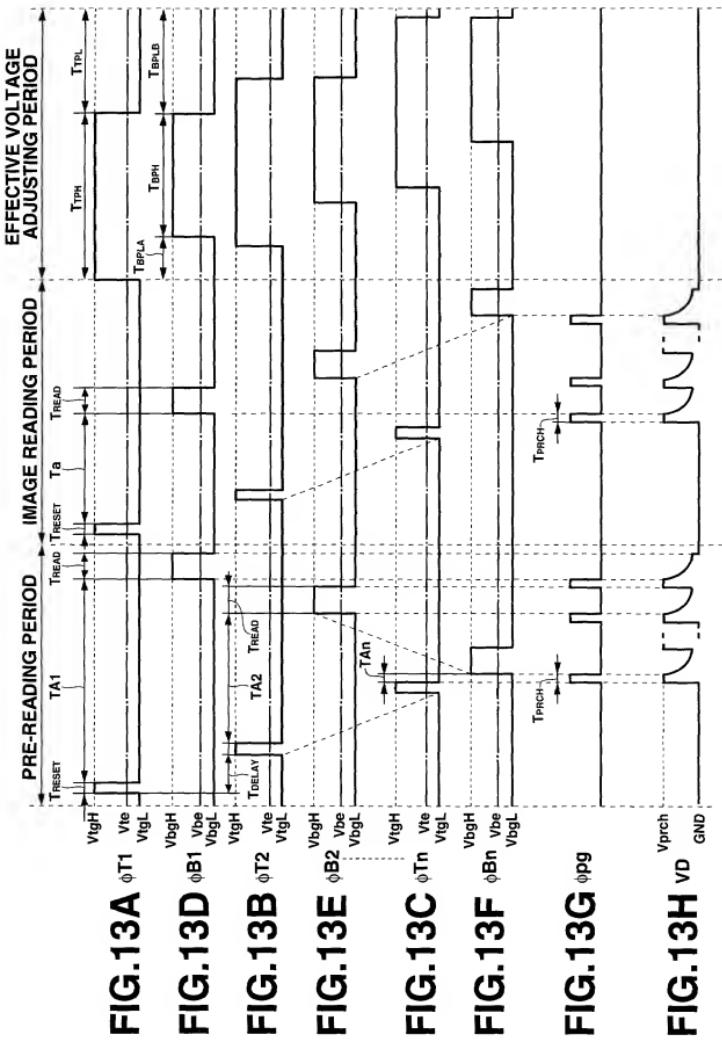












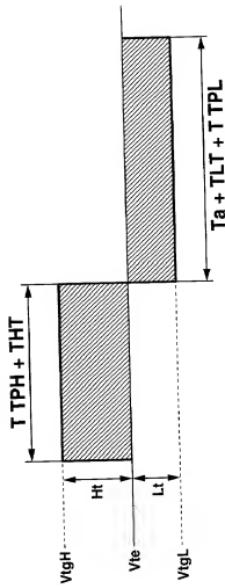


FIG.14A

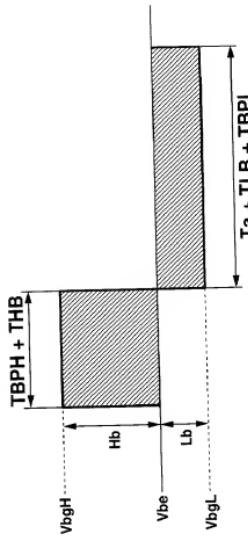


FIG.14B

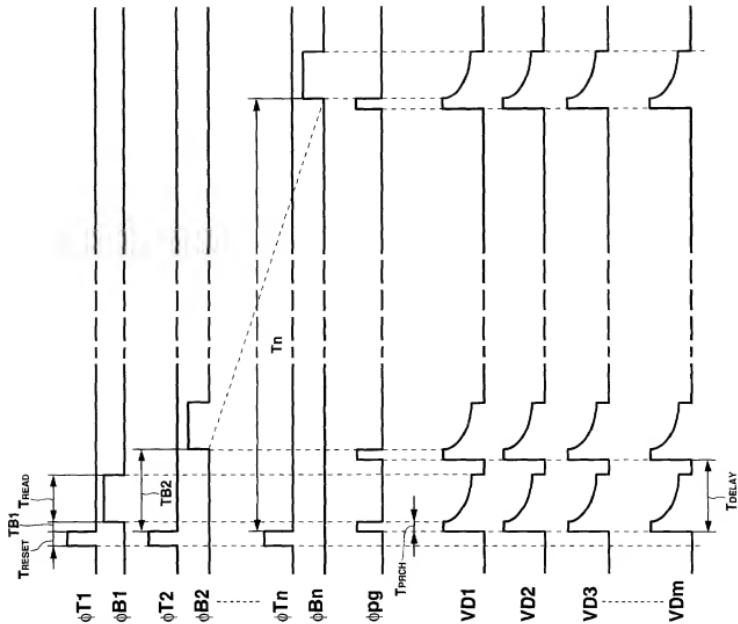


FIG. 15A
FIG. 15D

FIG. 15B
FIG. 15E

FIG. 15C
FIG. 15F
FIG. 15G

FIG. 15H

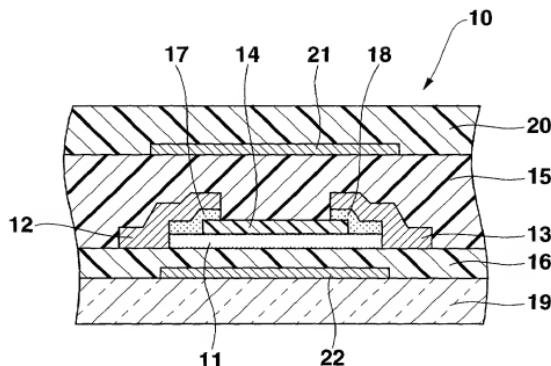


FIG.16A
PRIOR ART

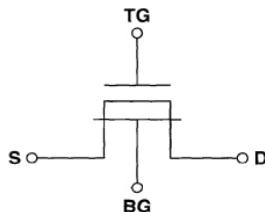


FIG.16B
PRIOR ART

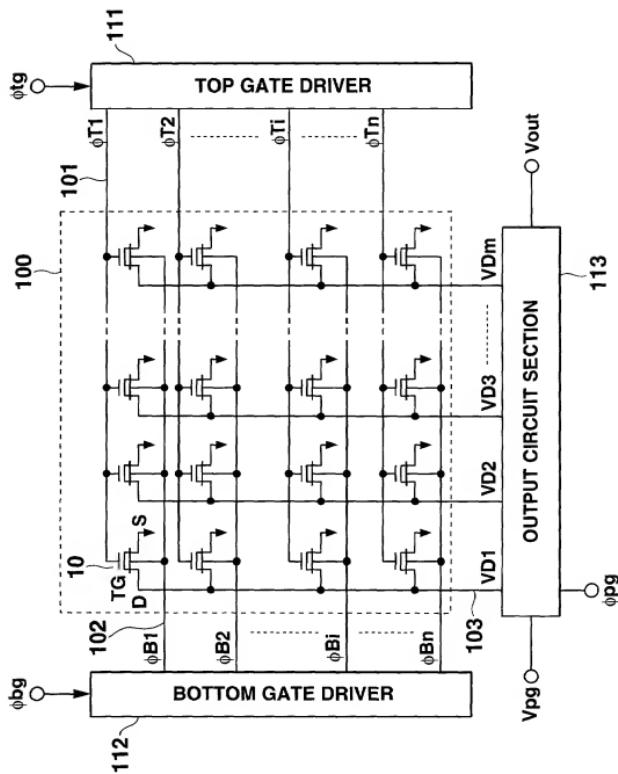


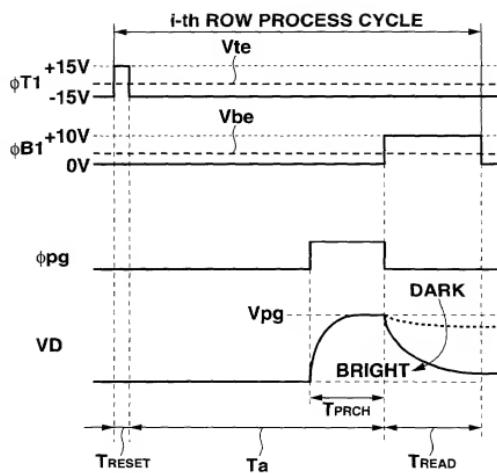
FIG.17
PRIOR ART

FIG.18A
PRIOR ART

FIG.18B
PRIOR ART

FIG.18C
PRIOR ART

FIG.18D
PRIOR ART



DECLARATION FOR PATENT APPLICATION

As a below named inventor, I declare: that I verily believe myself to be the original, first and sole (if only one individual inventor is listed below) or an original, first and joint inventor (if more than one individual inventor is listed below) of the invention in

PHOTODRIVE SYSTEM AND DRIVE CONTROL METHOD THEREOF

the specification of which is attached hereto unless the following box is checked.

was filed on _____ as United States Application or PCT International Application No. _____, and was amended on _____ (if applicable).

I hereby state that I have reviewed and understand the contents of the above identified specification, including the claims, as amended by any amendment referred to above.

I acknowledge the duty to disclose information of which is material to patentability as defined in 37 CFR 1.56.

I hereby claim foreign priority benefits under 35 U.S.C. 119(a)-(d) or 365 (b) of any foreign application(s) for patent or inventor's certificate, or 35 U.S.C. 365(a) of any PCT International application which designated at least one country other than the United States, listed below and have also identified below any foreign application for patent or inventor's certificate, or PCT International application having a filing date before that of the application on which priority is claimed:

Country	Category	Application No.	Filing Date	Priority Claim
Japan	Patent	11-271882	September 27, 1999	Yes
Japan	Patent	11-370533	December 27, 1999	Yes

And I hereby appoint Leonard Holtz (Reg. No. 22,974), Herbert H. Goodman (Reg. No. 17,081), Thomas Langer (Reg. No. 27,264), Marshall J. Chick (Reg. No. 26,853), Richard S. Barth (Reg. No. 28,180), Douglas Holtz (Reg. No. 33,902), and Robert P. Michal (Reg. No. 35,614) each of whose address is 767 Third Avenue - 25th Floor, New York, N.Y. 10017-2023, or any one of them, my attorneys with full power of substitution and revocation, to prosecute this application and to transact all business in the Patent & Trademark Office connected therewith, and request that correspondence be directed to Frishauf, Holtz, Goodman, Langer & Chick, P.C., 767 Third Avenue - 25th Floor, New York, N.Y. 10017-2023.

I declare further that all statements made herein of my own knowledge are true and that all statements made on information and belief are believed to be true, and further that these statements were made with the knowledge that willful false statements and the like so made are punishable by fine or imprisonment, or both, under Section 1001 of Title 18 of the United States Code and that such willful false statements may jeopardize the validity of the application or any patent issued thereon.

DECLARATION FOR PATENT APPLICATION

I declare further that my citizenship, residence and post office address are as stated below next to my name:

<u>Inventor: (Signature)</u>	<u>Date</u>	<u>Residence and post office address</u>
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<u>Makoto Sasaki</u> Makoto Sasaki	<u>Date: August 8, 2000</u>	<u>2-19-11-302, Daimachi, Hachioji-shi, Tokyo, Japan</u>
<u>Yoshiaki Nakamura</u> Yoshiaki Nakamura	<u>Date: August 8, 2000</u>	<u>9-7-1-5-402, Kabemachi, Ome-shi, Tokyo, Japan</u>
	<u>Date: _____</u>	<u>Citizen of: Japan _____</u>
	<u>Date: _____</u>	<u>Citizen of: Japan _____</u>
	<u>Date: _____</u>	<u>Citizen of: Japan _____</u>
	<u>Date: _____</u>	<u>Citizen of: Japan _____</u>
	<u>Date: _____</u>	<u>Citizen of: Japan _____</u>